

VOICE OF THE ENGINEER



Turning layoff lemons into start-up lemonade Pg 22

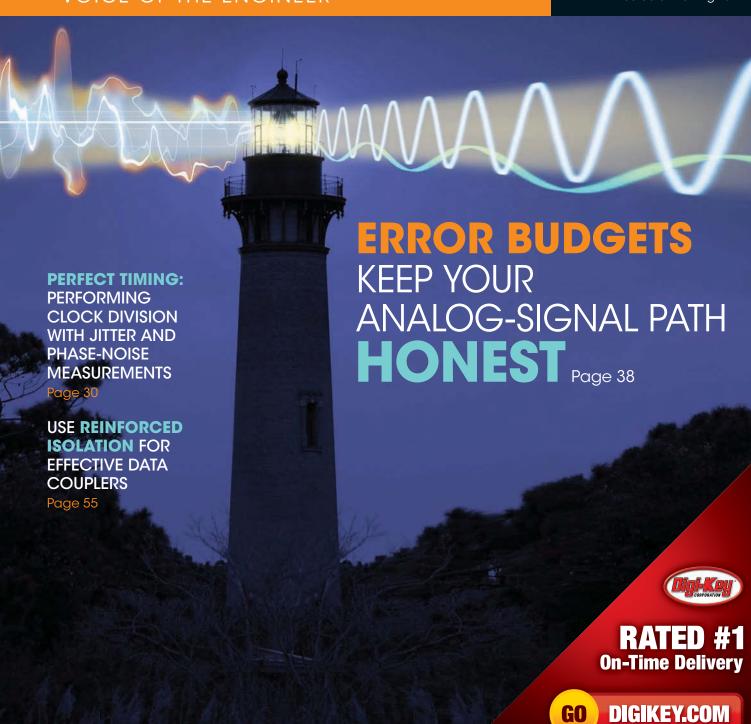
EDN.comment Pg 12

Baker's Best Pg 24

Prying Eyes: Slam Stick Pg 26

Design Ideas Pg 61

You auto know Pg 70



2011 MOST PREFERRED DISTRIBUTOR

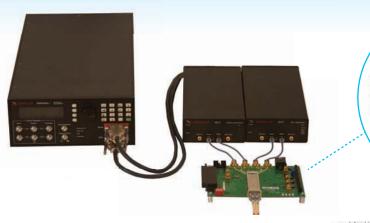






17 Gb/s Stressed BERT Solution for 16x Fibre Channel (16GFC) and InfiniBand FDR

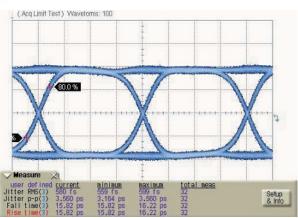
The highest performance solution for transceiver testing at 14 Gb/s





Key Features

- 3-17 Gb/s data rate
- Built-in selection of PRBS and common telecom/datacom test patterns
- Fully programmable user-defined patterns
- Remote heads place signal very close to DUT
- Compact size (4" x 8.5" x 17")



The speed you need - the price you can afford

Affordability and excellent broadband performance make the SSB17 the ideal solution for transceiver testing and verifying compliance to common standards, such as:

- 16x Fibre Channel (16GFC)
- InfiniBand FDR
- PCI Express
- USB
- SATA

- Hypertransport
- Thunderbolt
- DisplayPort
- SFP, SFP+, and XFP



Affordability without compromise



How to pick the perfect inductor for your LED driver application

IC reference designs are a good start. But what if you want to optimize the driver inductor for size, efficiency or price?

Or evaluate newer, high performance parts that weren't available

when the reference design was created?

Then you'll want to check out the new

Our new LED Design Center lets you:

- Search by IC to find all matching inductors
- Compare DCR, current rating, size and price
 - Analyze all core and winding losses Request free evaluation samples

www.coilcraft.com/LED

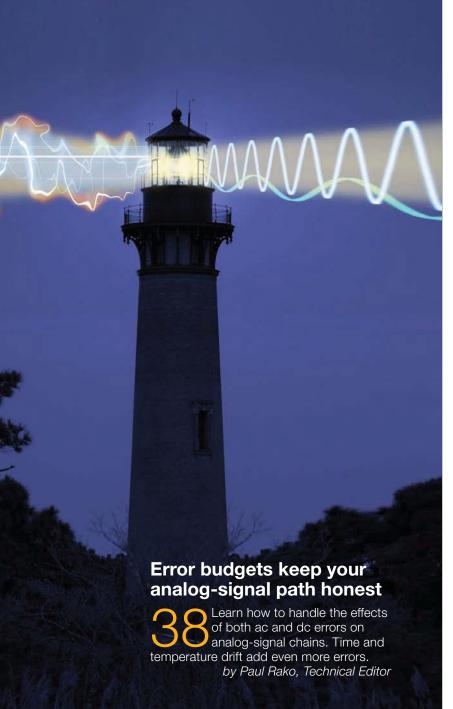
LED Design Center on the Coilcraft web site. It's filled with interactive tools that let you compare hundreds of inductors for all LED driver topologies, including SEPIC.

To start your search for the per-

fect LED driver inductor, mouse over to www.coilcraft.com/LED







EDN contents

10.20.17



Perfect timing: performing clock division with jitter and phase-noise measurements

As clock speeds and communication channels operate at ever-higher frequencies, accurate jitter and phase-noise measurements become more important, even as they become more difficult and expensive to manage. Some practical pointers and observations assist in handling these problems.

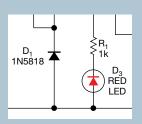
by Howell Mitchell, Silicon Laboratories

Use reinforced isolation for effective data couplers

55 Understand the requirements and mandates for electric-shock safety with respect to this common component. by Mark Cantrell, Analog Devices Inc

COVER: IMAGE: THINKSTOCK / ISTOCK

DESIGNIDEAS



- 61 Use a self-powered op amp to create a low-leakage rectifier
- 62 Simple reverse-polarity-protection circuit has no voltage drop
- 64 Series-LC-tank VCO breaks tuning-range records
- Find out how to submit your own Design Idea: http://bit.ly/DesignIdeasGuide.

[www.edn.com] OCTOBER 20, 2011 | **EDN** 5



Authorized Distributor





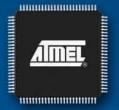




























Advanced semiconductor solutions to fuel your creativity.

Come to Mouser first for what's next from these industry leaders.



The Newest Products for Your Newest Designs®



a tti company

A BERKSHIRE HATHAWAY COMPANY

contents 10.20.11



- 15 FSW analyzer shows multiple measurements in single window
- 16 ST adds Cortex-M4 devices to STM32 portfolio
- 18 Integer-N frequency synthesizer integrates VCO, –103-dB spurious output
- 18 FPGA provides a board tester in a chip

- 20 App enables consumer conveniences with wireless memory, NFC technology
- 20 Researchers aim for energy-harvesting CPUs
- 22 **Voices:** Gordon Nuttall: turning layoff lemons into start-up lemonade

DEPARTMENTS & COLUMNS





- 9 EDN online: Join the conversation; Content; Engineering Community
- 12 EDN.comment: Thank you, Steve Jobs
- 24 Baker's Best: Designing with temperature sensors, part two: thermistors
- 26 Prying Eyes: Evaluate your application's energy-harvesting vibrational profile with a Slam Stick
- 28 Mechatronics in Design: No fighting
- 67 **Product Roundup:** Amplifiers, Oscillators, and Mixers
- 70 Tales from the Cube: You auto know

EDN® (ISSN# 0012-7515) is published semimonthly by UBM Electronics, 600 Community Drive, Manhasset, NY 11030-3825. Periodicals postage paid at Manhasset, NY, and at additional mailing offices. SUBSCRIPTIONS—Free to qualified subscribers as defined on the subscription card. Rates for nonqualified subscriptions, including all issues: US, \$150 one year; \$250 two years; \$300 three years. Except for special issues where price changes are indicated, single copies are available for \$10 US and \$15 foreign. For telephone inquiries regarding subscriptions, call 847-559-7597. E-mail: edn@omeda.com. CHANGE OF ADDRESS—Notices should be sent promptly to PO Box 47461, Plymouth, MN 55447. Please provide old mailing label as well as new address. Allow two months for change. NOTICE—Every precaution is taken to ensure accuracy of content; however, the publishers cannot accept responsibility for the correctness high in information supplied or advertised or for any opinion expressed herein. POSTMASTER—Send address changes to EDN, PO Box 47461, Plymouth, MN 55447. CANADA POST: Publications Mail Agreement 40612608. Return undeliverable Canadian addresses to BleuChip International, PO Box 25542, London, ON N6C 682. Copyright 2011 by United Business Media. All rights reserved. Reproduction in whole or part without written permission is prohibited. Volume 56, Number 20 (Printed in USA).

Benchmark MOSFETs

DC-DC Buck Converter and POL Applications

		2	er -
SO-8		331	
Part	V	nC	$m\Omega$
IRF8788PBF	30	44	2.8
IRF8714PBF (Ctrl)	30	8.1	8.7
IRF7862PBF (Sync)	30	30	3.7

IGK				
PQFN (5x6)				
Part	V	nC	$\mathbf{m}\Omega$	
IRFH5303	30	15	4.2	
IRFH5304	30	16	4.5	
IRFH5306	30	7.8	8.1	
IRFH5301	30	37	1.9	
IRFH5302	30	4.8	2.1	
IRFH5302D	30	26	2.5	

PQFN (3x3)			
Part	V	nC	$\mathbf{m}\Omega$
IRFHM831	30	7.3	7.8
IRFHM830	30	15	3.8
IRFHM830D	30	13	4.3

TOR E





For more information call 1.800.981.8699 or visit www.irf.com



THE POWER MANAGEMENT LEADER



Distributed

Factorized

Power Management

Innovation

Integration

Performance

Speed

Efficiency

Flexibility

More **Density**

Powers More Functionality in Less Space

Density drives product performance and efficiency. For decades, we've delivered high-density power management products that enable customers to pack more functionality in less space. We set the benchmark at 1,300 W/in³. This enables our customers to deliver category-changing products in diverse markets – from supercomputers, defense and aerospace to communications, industrial and transportation.

Don't let power be the limiting factor in your design and product vision.

Efficiency. Flexibility. Density.

Trust your product performance to Vicor.



Support

Expertise

Productivity

Reliability

Qualified



The Power Behind Performance

and online



JOIN THE CONVERSATION

Comments, thoughts, and opinions shared by EDN's community

In response to "Buyers of electric vehicles (EVs) may be very disappointed," posted in Patrick Mannion's Design Cycle blog at http://bit.ly/nyLSTu, Watashi commented:

"When ultra-capacitors and high-temperature superconductor motors sell for the same (or slightly higher) price point as batteries and conventional motors, EVs may be acceptable to the market. Cost/benefit ratios are what drive human nature, and unfortunately, EVs suffer tremendously in that arena."

In response to "Hackers liberate intelligent Christmas lights," posted in Margery Conner's PowerSource blog at http://bit.ly/q20eYl, William Ketel commented:

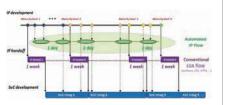
"While it is possible that the LED portion will last that long ... there are a lot of much weaker links in the chain that will fail far sooner. ... After all, the primary design target of any consumer good is minimum cost to produce. That is also the secondary design target. I am not aware of durability being on the list, even. So what becomes of all those Internet addresses after the part fails? Has anybody ever thought of that?"

In response to "Doing too much at once?" posted in Brian Bailey's Practical Chip Design blog at http://bit.ly/npbJg9, Andy T commented:

"Hiding features is fine, but I still want access to ALL of the hardware with an 'unhide' in the event I need, or want, to get clever with the capability of the device at the configuration bit level—an unforeseen (by 'them') or proprietary (my) capability. FPGA vendors are among the worst for this FOS (fear of support). Having worked for one, I know what was in the chip and what was not 'allowed' for customers to access."

EDN invites all of its readers to constructively and creatively comment on our content. You'll find the opportunity to do so at the bottom of each article and blog post. To review current comment threads on EDN.com, visit http://bit.ly/EDN_Talkback.





A PRACTICAL APPROACH TO IP-QUALITY INSPECTION

A robust process that can automatically assess IP quality at incoming inspection can have a large impact on your schedule and overall well-being.

http://bit.ly/pW1MOv

CREE TAKES A PAGE FROM AMAZON'S PLAYBOOK WITH ITS NEW LED TEMPO SERVICE

Jeff Bezos, head of Amazon, has been quoted as saying, "There are two ways to build a product. The first: a company starts with their strengths and builds to the needs of the consumer. The second: a company starts with the needs of the consumer and builds [into] the strengths of the company." Like Amazon, Cree is another rare company that does both.

http://bit.ly/pRZB4I



ENGINEERING COMMUNITY

Opportunities to get involved and show your smarts

ARM TechCon-http://bit.ly/EDN_ARMTechCon

The event, which starts October 25, aims to connect, instruct, advise, and enable the world of electronic and computer design. This year's technical conference offers two distinct elements: Chip Design Day, a one-day intensive conference for chip-design teams working with ARM silicon IP and tools; and Software and Systems Design Days, two days geared toward those interested in building ARM-based modules, boards, and systems.

[www.edn.com] OCTOBER 20, 2011 | **EDN** 9

SPACE SAVING TECHNOLOGY Inductors from 19" ht. **PICO**

Over 5000 Standard Surface Mount and

Thru-Hole Models

Impedance Levels 10 ohms to 250k ohms, Impedance Levels 3 Watts, Frequency Power Levels to 3 OHz to 250Hz. All units Response ±3db 20Hz to MIL-PRF-27. Response ±3db 20Hz to MIL-PRF-27. Manufactured and tested to MIL-PRF-27. OPL Units available.

QPL Units available.

Ideal for Noise, Spike and Power Filtering

Ideal for Noise, Spike and Power Found

Regulators

Applications in Switching Regulators

Converters and Switching

Multiplex Data Bus

Pulse Transformers

Plug-In units meet the requirements

Plug-In Units PRF 21038/27

of QPL-MIL-PRF 21038/27.

Surface units are electrical
of QPL-MIL-PRF 21038/27.

Pulse Transformers

10 Nanoseconds to 100 Microsecond,
10 Nanoseconds Volt Microsecond,
ET Rating to 150 Volt to MIL-PRF-21038.
Manufactured and tested to MIL-PRF-21038.

Transformers
Trans DC-DC Converter

Power Transformers Voltages 5V Power Transformers Voltages 5V 0.4 Watts to 150 Watts. Secondary PRF-27 0.4 Watts to 150 Watts wanufactured to MIL-PRF-27 to 300V. Units manufactured to available). Grade 5, Class S (Class V, 155°C available). 400Hz/800Hz

Electronics,

143 Sparks Ave. Pelham, NY 10803 • Call Toll Free 800-431-1064 • Fax: 914-738-8225

Send for free 180 pg PICO Catalog

See PICO's full Catalog Immediately on the internet www.picoelectronics.com

E-mail: info@picoelectronics.com



EDN

BRAND DIRECTOR, EDN

Jim Dempsey 1-440-333-3040; jim.dempsey@ubm.com

DIRECTOR OF CONTENT, EDN AND DESIGNLINES

Patrick Mannion 1-631-543-0445; patrick.mannion@ubm.com

EXECUTIVE EDITOR, EDN AND DESIGNLINES

Rich Pell 1-516-742-0027; rich.pell@ubm.com

MANAGING EDITOR

Amy Norcross

Contributed technical articles
1-781-869-7971;
amy.norcross@ubm.com

MANAGING EDITOR, ONLINE

Suzanne Deffree Electronic Business, Distribution 1-631-266-3433; suzanne.deffree@ubm.com

TECHNICAL EDITOR

Margery Conner Power Sources, Components, Green Engineering 1-805-461-8242; margery.conner@ubm.com

TECHNICAL EDITOR

Paul Rako Design Ideas, Analog, RF, PCB Design 1-408-745-1994; paul.rako@ubm.com

SENIOR ASSOCIATE EDITOR

Frances T Granville 1-781-869-7969; frances.granville@ubm.com

ASSOCIATE EDITOR

Jessica MacNeil 1-781-869-7983; jessica.macneil@ubm.com

CONTRIBUTING TECHNICAL EDITORS

Dan Strassberg,
strassbergedn@att.net
Stephen Taranovich,
staranovich@yahoo.com
Brian Bailey,
brian_bailey@acm.org
Robert Cravotta,
robert.cravotta@embeddedinsights.com

COLUMNISTS

Howard Johnson, PhD, Signal Consulting Bonnie Baker, Texas Instruments Pallab Chatterjee, SiliconMap Kevin C Craig, PhD, Marquette University

VICE PRESIDENT/DESIGN DIRECTOR

Gene Fedele

CREATIVE DIRECTOR

David Nicastro

ART DIRECTOR

Giulia Fini-Gulotta

PRODUCTION

Adeline Cannone, Production Manager Laura Alvino, Production Artist Yoshihide Hohokabe, Production Artist Diane Malone, Production Artist

EDN EUROPE

Graham Prophet, Editor, Reed Publishing gprophet@reedbusiness.fr

EDN ASIA

Huang Hua,
Operations General Manager
huang.hua@ednasia.com
Grace Wu, Associate Publisher
grace.wu@ednasia.com
Vivek Nanda, Executive Editor
vnanda@globalsources.com

EDN CHINA

Huang Hua,
Operations General Manager
huang.hua@ednchina.com
Grace Wu, Associate Publisher
grace.wu@ednasia.com
Jeff Lu, Executive Editor
jeff.lu@ednchina.com

EDN JAPAN

Masaya Ishida, Publisher mishida@mx.itmedia.co.jp Makoto Nishisaka, Editor mnishisa@mx.itmedia.co.jp

UBM ELECTRONICS MANAGEMENT TEAM

Paul Miller,

Chief Executive Officer, UBM Electronics and UBM Canon (Publishing)
Brent Pearson, Chief Information Officer David Blaza, Senior Vice President Karen Field,
Senior Vice President, Content Jean-Marie Enjuto,
Vice President, Finance Barbara Couchois,
Vice President, Partner Services and Operations
Felicia Hamerman,
Vice President, Marketing
Amandeep Sandhu,

Director of Audience Engagement and Analytics



For a complete list of editorial contacts, see http://ubmelectronics.com/editorial-contacts



EFFICIENCY REDEFINED.

Discover a new standard in High Voltage LED: The new EVERLIGHT HV Series combines the efficiency of a DC LED with the simplicity of an AC LED. The ultra-compact design, flicker-free brightness and durability make the new EVERLIGHT HV 1W and HV 4W LED Series the first choice for your fixture solutions. Saving valuable resources was never a smarter option.

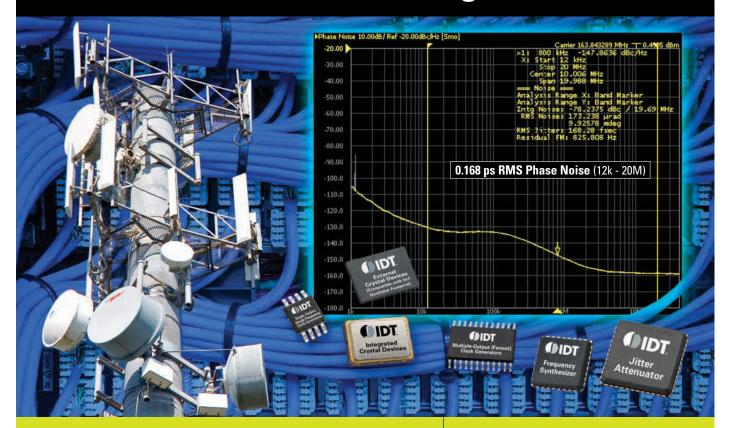
For more light and information enter





Additional comments here: "Steve Jobs life lessons," http://bit.ly/EDN_SteveJobs

Integrated D evice Technology FemtoClock NG – When a Trillionth Of a Second is Just Too Long



The FemtoClock Next Generation (NG) clock synthesiser family allows engineers to generate almost any output frequency from a fixed frequency crystal, and to meet the challenges of the most demanding timing applications.

Use of a single source to generate multiple clocks often leads to increased susceptibility to power supply noise and restrictions on multiplication factors. IDT's technology effectively eliminates these problems by doubling the power-supply noise rejection (PSNR) of previous generation devices while also introducing the potential for virtually limitless customization of output frequency.

An innovative fractional multiplier PLL architecture introduces the flexibility for

engineers to generate any output frequency from any input frequency. And the advanced design of the FemtoClock NG family achieves greater than 80 dB of PSNR to make the devices immune to power-supply noise.

Other performance benefits of FemtoClock NG technology include low power consumption and a clocking performance of under 0.5 ps RMS phase noise jitter! The devices offer standard outputs such as differential LVPECL, LVDS and single-ended LVCMOS, providing a precise fit to any application.

With FemtoClock NG technology, IDT has eliminated the most challenging aspects of silicon-based clock design and introduced an unprecedented level of flexibility for clocking in high-performance applications.



The Analog and Digital Company™

For more information visit us online at www.IDT.com







FSW analyzer shows multiple measurements in single window

ohde & Schwarz's new FSW signal and spectrum analyzer comes in three models that cover 2 Hz to 8, 13, or 26.5 GHz and comes in 80- and 160-MHzbandwidth versions. As the eventual replacement for the FSU spectrum analyzer and the FSQ signal analyzer, the FSW targets use in development laboratories in aerospace, defense, and communications. The FSU has a 20-Hz to 67-GHz frequency, and the FSQ has a 120-MHz bandwidth and a 20-Hz to 40-GHz frequency. Those units will remain in production for two to three years, and the FSW's specification will expand to match its predecessors' bandwidth and frequency.

A 12.1-in. touchscreen enables a multiview function to simultaneously display the results of multiple applications and eliminates timeconsuming switching between the applications. At a 10-kHz carrier offset, the FSW achieves a phase-noise specification of less than -137 dBc at 1 Hz, which is as much as 10 dB less than comparable instruments. This spec is important for developers of RF components and complete systems for radar applications.

With the optional FSW-K6, the FSW also supports analysis of pulsed signals. It allows the unit to measure wideband, hopping, and chirp signals for wireless standards, such as 802.11ac. The FSW also enables developers to quickly detect spurious emissions.

The FSW can optionally include FSW-B13 switchable highpass filters for carrier frequen-

> The FSW analyzer has a 12.1-in. touchscreen, enabling a multiview function to simultaneously display the results of multiple applications.

cies as high as 1.5 GHz for harmonic measurements on transmitter systems, resulting in improved dynamic range over conventional spectrum analyzers and eliminating the need for external filters. This feature facilitates test-system setup for GSM (global-systemfor-mobile)-communication, CDMA (codedivision-multiple-access), WCDMA (wideband-CDMA), LTE (long-term-evolution), and TETRA (terrestrial-trunked-radio) systems, for example.

The company's Legacy Pro technology enables the FSW to support the remotecontrol command sets of Rohde & Schwarz and other vendors' instruments. Users can exchange the FSW's internal solid-state disk for a neutral solid-state disk and can send their instruments for calibration without having any confidential test data leave the lab. Device-specific alignment data remains in the analyzer, separate from the user data.

-by Colin Holland

⊳Rohde & Schwarz,

www.rohde-schwarz.com.

"As a consumer, my main concern ... about modern gadgetry is that so often ... [its] accompanying sophistication makes it unreliable! **Instead of a KISS** [keep it simple, stupid] philosophy, they put in frilly features, peripheral to the product's main intended function, and it tends to [wear out] first and make the whole widget irreparable and disposable."

-Reader "Frank," in EDN's Talkback section, at http://bit. ly/pTtg4F. Add your comments.



[www.edn.com]



ST adds Cortex-M4 devices to STM32 portfolio

■ TMicroelectronics based its new STM32 F4 series of microcontrollers on the ARM Cortex-M4 core, which adds signal-processing capabilities and faster operations. The STM32 F4 series extends the STM32 portfolio and has more than 250 compatible devices in production, including the F1 series, the F2 series, and the ultra-low-power L1 series. The company is widening its target applications with the STM32 F4 series. Its single-cycle DSP instructions should provide access to the DSC (digital-signal-controller) market, which requires high computational capability and DSP instructions for applications such as high-end motor control, medical equipment, and security.

The F4 series provides a pin- and software-compatible upgrade from the STM32 F2 series with more SRAM; higher performance; and peripherals for imaging, connectivity, and encryption. The F4 series operates at 168 MHz compared with 120 MHz for the F2 and provides single-cycle DSP-instruction support and an FPU (floating-point unit), 192 kbytes of SRAM compared with 128 kbytes for the F2, and 512 kbytes to 1 Mbyte of embedded flash memory.

The F4 series provides ultrafast data transfers, with a sevenlayer, multiple-AHB (advanced high-performance-bus) matrix and multiple DMA (direct-memory-access) controllers, which allow concurrent execution and data transfers. The integrated single-precision FPU boosts the execution of control algorithms, improves code efficiency, eliminates scaling and saturation, and allows the use of metalanguage tools.

The device integrates a reset circuit, PLLs (phase-locked loops), and a less-than-1- μ A real-time clock with less-than-1-sec accuracy. It has 4 kbytes of backup SRAM to save data in standby or battery-backup mode. Typical real-time-clock power consumption is less than 1 μ A in battery-voltage mode, and an internal voltage regulator with power scaling enables the trade-off of performance versus power consumption.

Connectivity includes a camera interface; a cryptography/hash-encryption hardware processor; a 10- and 100-GbE (gigabit-Ethernet) MAC (media-access controller) with IEEE 1588 Version 2 support; and two USB (Universal Serial Bus) OTG (On-The-Go) ports, one of which has HS (high-speed) support.

The device includes a dedicated audio PLL and two full-duplex I²S (inter-integrated-circuit-sound) ports. It also has as many as 15 communication interfaces, including six

USARTs (universal synchronous/asynchronous receivers/transmitters) operating as fast as 10.5 Mbps, three SPIs (serial-peripheral interfaces) operating as fast as 42 Mbps, three I²C (inter-integrated-circuit) ports, two CAN (controller-area-network) inter-



The F4 series of microcontrollers provides a pin- and software-compatible upgrade from the STM32 F2 series with more SRAM; higher performance; and peripherals for imaging, connectivity, and encryption.

faces, and one SDIO (serial-digital input/output) interface. The analog circuits include two 12-bit DACs; three 12-bit ADCs with rates as high as 2.4M or 7.2M samples/sec in interleaved mode; and as many as 17 timers, including 16- and 32-bit devices operating as fast as 168 MHz.

Four variants are available. The STM32F405x has timers, three ADCs, two DACs, serial interfaces, an external memory interface, a real-time clock, a CRC (cyclic-redun-

dancy-check)-calculation unit, and an analog true-random-number generator, as well as a USB OTG FS (full-speed)/HS interface. It is available in WLCSP64, LQFP64, LQFP100, and LQFP144 packages with 1 Mbyte of flash.

STM32F407 products add

a second FS-only USB OTG interface; an integrated 10- and 100-GbE MAC supporting both an MII (media-independent interface) and an RMII (reducedmedia-independent interface), with IEEE-1588 precise-time protocol Version 2 hardware support and an 8- to 14-bit parallel camera

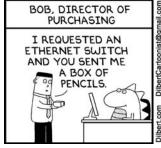
interface allowing the connection of a CMOS camera sensor that supports speeds as high as 67.2 Mbytes/sec. Devices are available in LQFP100, LQFP144, and LQFP/BGA176 packages, with 512 kbytes to 1 Mbyte of flash.

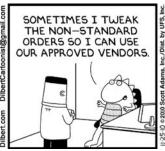
The STM32F415 and STM-32F417 parts add a cryptography/hash-encryption processor to the STM32F405 and STM32F407. The processor has hardware acceleration for AES (Advanced Encryption Standard) 128, 192, and 256; Triple DES (Data Encryption Standard); the MD5 (Message Digest 5) algorithm; and the SHA-1 (Secure Hashing Algorithm-1). The devices are in volume production, and prices begin at \$5.74 (1000) for the STM32F407VET6 with 512 kbytes of flash and 192 kbytes of RAM in an LQFP100 package. - by Colin Holland

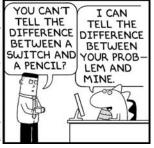
STMicroelectronics,

www.st.com.

DILBERT By Scott Adams







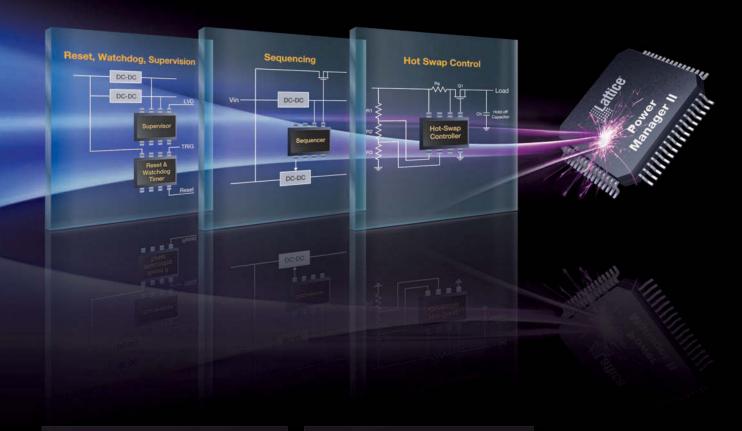
Supply Police Chicagonica Chic

Power Manager II. INTEGRATE POWER MANAGEMENT. LOWER COSTS.

Power Manager II features an innovative programmable core and precision analog sensors to reduce component count and increase reliability. Lattice programmability enables your power management design to meet changing requirements without major circuit redesign or a board re-spin.

Learn more about the cost-efficiencies of Power Manager solutions at:

latticesemi.com/powermanager



Foatures

- Charge pumps for hot swap MOSFET control
- PLD for flexible supply sequencing and reset generation
- 0.2% error (typ.) programmable comparators for fault detection
- Differential sensing for centralized control
- 10-bit ADC with I²C interface for system monitoring
- High volume pricing starts at <\$1.00

And more...

Benefits

- Integrate multiple functions to reduce BOM cost
- Increase fault coverage
- Reduce footprint
- Increase reliability
- Wide application coverage
- Reduce risks through programmability

And more...



latticesemi.com/powermanager



Integer-N frequency synthesizer integrates VCO, –103-dB spurious output

inear Technology's new LTC6946 integer-N frequency synthesizer integrates a VCO (voltage-controlled oscillator) and delivers -226-dBc (decibels referenced to the carrier)/Hz normalized, closed-loop, in-band phase noise; -274-dBc/Hz normalized, in-band flicker noise; and -103-dB spurious output. In a typical 900-MHz system, these features enable the device to achieve a closed-loop phase noise of -100 dBc/Hz at a 1-kHz offset.

The device is available in three versions: The LTC6946-1, LTC6946-2, and LTC6946-3 have frequency ranges of 2.24 to 3.74, 3.08 to 4.91, and 3.84 to 5.79 GHz, respectively. Each device has an on-chip output divider that is programmable from one through six to extend frequency coverage

to as low as 373 MHz.

The device integrates a lownoise, 5.7-GHz PLL (phaselocked loop), which includes a reference divider, a phase-

frequency detector with a phaselocked indicator, an ultra-lownoise charge pump, and an integer-feedback divider to achieve low-noise PLL operation. The PLL circuit tightly couples to a lownoise VCO and to internal selfcalibration to ensure optimum

VCO-resonant tuning. The VCO requires no external components. An on-chip SPI (serial-peripheral-interface)-compatible, bidirectional port allows

frequency tuning and control and read-back of register and loop-status information.

The frequency synthesizer enhances the performance of



The LTC6946 integer-N synthesizer integrates a VCO for improved performance.

multiband base stations supporting LTE (long-term-evolution), CDMA (code-division-multiple-access), WCDMA (wideband-CDMA), UMTS (Universal Mobile Telecommunications System), GSM (global-system-for-mobile)-communications, and WiMax (worldwide-operability-for-microwave-access) standards. The device suits use in point-to-point broadband wireless-access, military, avionics, and test-and-measurement applications.

The PC-based PLLWizard design-tool software is available to facilitate interactive control and interface with the LTC6946's evaluation board. Designers can download the tool from www.linear.com/ synthesizers and use it to perform simulations and optimization and then interactively verify their designs on a demonstration circuit. All versions of the LTC6946 operate at -40 to +105°C and are available in 4×5-mm, 28-lead, plastic QFN packages. Prices start at \$5.75 (1000). - by Fran Granville

Linear Technology Corp, www.linear.com/
product/LTC6946.

FPGA provides a board tester in a chip

Asset InterTech has expanded its ScanWorks platform for embedded-instrument engineers with tools to select instruments, set parameters, and insert them into FPGAs to function as PCB (printed-circuit-board) testers. The FCT (FPGA-controlled-test) system operates the board tester in a chip from a drag-and-drop user interface to perform validation, testing, and debugging. According to the company, escalating gate densities make FPGAs an effective platform for embedded test-and-measurement applications. Higher speeds and greater complexities have increased the electrical sensitivities of chips and boards to the point at which physical probes provide inadequate test coverage and unreliable results.

PCB-design projects can encounter delays because engineers cannot validate the hardware on the board until after completion of the firmware or operating-system-software development. FCT, in contrast, does not depend on any product software. Instead, designers can insert a board tester, bring up and wring out first prototypes of a design, and then remove the tester. If they need it later in the product's life cycle, they can

insert it again, or a part of it can remain in the FPGA.

ScanWorks automates practically all of the FCT process. It selects instruments or instrument functions from a library and matches them with a description of one of the supported FPGA devices in another ScanWorks library. After a user sets the configuration parameters on the selected instruments, ScanWorks automatically generates all of the constructs for the embedded tester, facilitates the synthesis of the instrument code into the firmware the FPGA requires, and creates the software image of the tester to program the FPGA. ScanWorks then inserts the tester in the FPGA and provides a drag-and-drop user interface to operate and manage the tester. FCT's abilities expand the coverage of ScanWorks' other nonintrusive technologies, including boundary-scan test, processor-controlled test, and high-speed-I/O validation. **ScanWorks FCT will become available in December** 2011 from Asset InterTech and its distributors. A development license sells for \$35,000.

-by Colin Holland

Asset InterTech, www.asset-intertech.com.

18 **EDN** | OCTOBER 20, 2011 [www.edn.com]

Rarely Asked Questions

Strange stories from the call logs of Analog Devices

Rotary Potentiometers: There Must Be a

Better Option

Q: I'm trying to use a potentiometer (pot) in the feedback loop of an op amp circuit, but the adjustment is too sensitive. Do you have any suggestions on how to improve the performance of this circuit?

A: The first thing I would tell you is to be careful when using pots in feedback loops, especially at higher frequencies. Wire wound pots have lots of inductance and can cause instability. Watch out for carbon pots as they are noisy.

Here are a few things you can try, however. Depending on your situation, you can add a series resistor and use the pot to "fine tune" the value you need. Sized appropriately, the pot sensitivity will be reduced greatly. You can also put the pot in parallel with the feedback resistor. Again, sizing the feedback resistor value is critical as to what contribution the pot will play. The advantage of this option is it allows you to go all the way to zero ohms.

A better option is to use a digitally controlled potentiometer or "digiPOT," which are extremely accurate and avoid typical pot issues such as wear out, vibration, drift, size, mechanical adjustment, and environmental issues, to name a few. Several options are available for the digital control (SPI, I²C, push button, and up/down interface), and the adjustment is accurate and repeatable. A digiPOT can also be used as a rheostat, which is a pot with one of the end terminals tied to the



wiper to form a variable resistor. digiPOTs work in both noninverting and inverting op amp configurations.

The bandwidth of these parts covers a wide range as a function of the resistor value. For example, a digiPOT set at 1K ohms has about 5 MHz of bandwidth, whereas a resistor setting of 10K ohms has a bandwidth of 500 kHz. These parts are extremely versatile and offer the designer a new tool for their "tool box." Low power, small footprint, and solid-state reliability make digiPOTs a very attractive alternative to the "old fashioned" option.

Even though they are simple building block devices (as most components are), there is a fair amount of detailed information to be considered. The datasheets for these devices (and all Analog Devices components) contain a wealth of comprehensive information, so a thorough read is recommended to optimize your design experience.

To Learn More About digiPOTs

http://dn.hotims.com/34946-1000



Contributing Writer
John Ardizzoni is a
Technical Product
Manager at Analog
Devices in the High
Speed Linear group.
John joined Analog
Devices in 2002, he
received his BSEE
from Merrimack College in N. Andover, MA
and has over 30 years
experience in the
electronics industry.

Have a question involving a perplexing or unusual analog problem? Submit your question to: www.analog.com/ askjohn

For Analog Devices' Technical Support, Call 800-AnalogD

SPONSORED BY



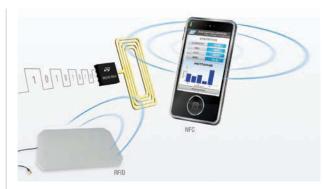


App enables consumer conveniences with wireless memory, NFC technology

TMicroelectronics recently introduced the M24LR64 wireless memory, which can transmit and receive information from an application to a smartphone containing NFC (near-field-communication) technology or to an industrial RFID (radio-frequency-identification) reader, allowing for rapid transactions, data exchange, object identification, and tracking.

NFC operates at 13.56 MHz and is finding use in smart-phones to enable customers to make payments, such as for public transit and in convenience stores, using their mobile devices. The technology can also permit communication between NFC-enabled devices.

According to market researcher IHS iSuppli, partner-



The M24LR64 wireless memory operates on the Android operating system, which connects an NFC-enabled smartphone to a prototype temperature recorder.

ships between major US wireless carriers and credit-card companies will drive NFC technology into 30.5% of all handsets in 2015.

The dual-EE (energy-efficient) application, which operates on the Android operating

system, is fully compatible with STMicroelectronics' M24LR64 wireless memory. The application connects an NFC-enabled smartphone to a prototype temperature recorder featuring the M24LR64 and demonstrates data transfer and storage. These

features can work in medical devices, home appliances, consumer electronics, and meters.

The dual-interface M24LR64 EEPROM can connect directly to wireless antennas, such as those in RFID tags, to transfer data through the energy in radio waves between an RFID or an NFC reader and an electric tag attached to an object, allowing reading or updating of the equipment when it is off. It communicates with RFID and ISO15693-capable NFC readers and with the system's own processors. It also features a 32-bit-password data-protection scheme, enabling control of wireless read- and write-memorv access. The device has a low-power wired-I2C (interintegrated-circuit) interface to a microcontroller or a chip set and sells for 72 cents (1000).

—by Fran Granville ▶STMicroelectronics, www.st.com.

Researchers aim for energy-harvesting CPUs

he National Science Foundation and the Nanoelectronics Research Initiative of Semiconductor Research Corp recently awarded a team of researchers from VCU (Virginia Commonwealth University) two grants totaling \$1.75 million to create powerful, energy-efficient computer processors that can run an embedded system without battery power. The researchers based their findings on a paper published by the VCU research team in the August issue of Applied Physics Letters. The technique replaces transistors with tiny nanomagnets that can also process digital information, theoretically reducing the heat dissipation by a factor of 1000 to 10,000, according to VCU.

Researchers at the VCU School of Engineering led the team, which is working with colleagues from the University of Virginia—Charlottesville, the University of Michigan—Ann Arbor, and the University of California—Riverside, to translate its theoretical work into a computing device.

"The purpose of this work is to estab-

lish a new paradigm for digital computing, which will be extremely energyefficient and hopefully allow us to pack more and more computing devices onto a chip

without having to worry about excessive heat generation," says Supriyo Bandyopadhyay, co-principal investigator for the study and a professor of electrical and computer engineering at VCU. "This [discovery] will allow us to increase the computational prowess of computers beyond what is available today."

As processors have shrunk in accordance with Moore's Law, engineers are packing more and more transistors onto a chip, creating a challenge for efficiently removing the heat that the transistors generate. Reducing the amount of dissipated heat when the transistor switches is considered to be the best approach to alleviating this problem.

A new technique replaces transistors with tiny nanomagnets that can also process digital information, theoretically reducing the heat dissipation by a factor of 1000 to 10,000 (courtesy Virginia Commonwealth University).



According to Bandyopadhyay and Jayasimha Atulasimha, an assistant professor of mechanical and nuclear engineering in the VCU School of Engineering and coprincipal investigator on the project, this research could lead to a type of digital computing system for medical devices, such as processors that physicians could implant in an epileptic patient's brain that monitor brain signals to warn of impending seizures. This processor would run by harvesting energy only from the patient's head movements, without requiring a battery, they claim.

—by Dylan McGrath ⊳Virginia Commonwealth University, www.vcu.edu.

Innovation & Passion

We've been revolutionizing measurement technology since 1933. The world's first vector network analyzer. The first single-box 67 GHz spectrum analyzer. A vector network analyzer with an extraordinary frequency range of 500 GHz. The first combined phase noise and spectrum analyzer in one instrument. Our list of innovations for the aerospace and defense industries goes on.



VOICES

Gordon Nuttall: turning layoff lemons into start-up lemonade

rmed with a bachelor's degree in electrical engineering, Gordon Nuttall went from college to work for Hewlett-Packard, where he put his engineering skills to use in areas such as digital imaging and new-business creation. Thirty-one years later, during the economic downturn of 2008, Nuttall was one of the many tech-industry employees to be laid off. Instead of taking an early retirement or seeking a position similar to the one he had just lost, Nuttall did what some might call crazy: He set out to form a start-up. Now, three years later, Nuttall and the team at Couragent Inc aren't just surviving the still-cold economy, they are growing and moving their Flip-Pal mobile scanner toward new markets. The chief executive officer recently spoke with EDN about the choices he made in turning a layoff into an opportunity. Excerpts of that conversation follow. Look for the full interview at www.edn.com/111020pulsea.

You had been with HP for more than 30 years. How did you react to being downsized in 2008?

We call it "WFRed." WFR: workforce reduction. So we called ourselves the WFRers. We formed a group of people who met socially and did things together to replace that interaction you would get in the company. That social interaction tends to get lost when you leave a company.

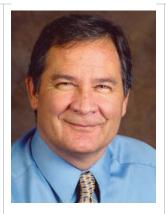
Are these the people who helped you start Couragent?

Some, yes. But others I had known from before and are just really talented people. That [fact] was one thing that was instrumental about the [large-scale industry] downsizing and economy: It makes for a lot of really fantastic talent out there. If I started a new company, I

would never be able to recruit those people away from their old jobs. But a start-up gives people a chance to think about a new way of doing their work and what their real passion is. That's one of the ways I think the downsized economy can be turned into lemonade rather than lemons. People get a chance to do something that, in a corporate gig, they might not have ever ventured out to try. Sometimes you need to be upstaged out of your comfort zone, and then you find out that you can do so much more than you ever thought you would within the confines of a company.

Where did the name Couragent come from?

We started the company based on our five foundational values: courage, integrity, collaboration, innova-



tion, and care. When you take the first four letters of courage, our first value—cour—means heart in the old Latin derivative. And then "agent." When we talk to our team, they are "couragents," agents of heart. In that talk, we speak not only from our logic but also from our hearts, and the things that matter to us are not just facts and figures but also who we are as a people. The name reflects a lot about our company.

Any words of advice for the many talented engineers out there who have been downsized and may be wondering what to do next?

It's very common to want to find a job like the one that you had before. Well, that's kind of slim pickings these days. I was a program manager, and big corporations aren't really hiring at that management level. I became really involved in professional-networking groups. I really encourage people to join a networking group or to become more proficient at talking with people and getting to know other areas that you normally would not have come in contact with when you were in a company. Be out there, and do a lot more networking.

I also think that the employment model of the future and

the one we are using with Couragent involves multiple streams of income, where people are independent consultants and they work under a 1099 contract to one or maybe several gigs at the same time. I would suggest that people form LLCs [limited-liability companies] to take advantage of tax benefits. And go to the conventions; join the associations that are the industry-leading professional organizations. It looks good on a résumé, and it keeps you speaking the general lingo of the industry.

You left college, went into this corporate world at HP, were downsized, and are now here in this whole new life. Are you happy?

I'm pursuing my passion. I sometimes will give presentations to groups, and I will say that I'm unemployable now. For me to go back to a corporate gigwhere you have to do all the politics, and decisions take forever, and you have to get three doubles of an approval-I could never go back to that. With this small company, when we need to make a decision, we just put our heads together and go for it. Once you've experienced that passion for action, you might never want to go back. Some days I wonder what the heck I am doing starting a company at 56 years old. Maybe there is a fine line between crazy and totally gassed.

Everybody thinks it's the younger folks who are doing all the entrepreneurial, innovation stuff. But we're doing a great job, enjoying ourselves, and have a very solid business plan So this has got a lot of nice aspects to it.—interview conducted and edited by Suzanne Deffree

Quality & Reliability

Expect only the best. Products of exceptional quality and services that focus on your needs. We help protect your investment with reliable, long-term customer support and calibration tools for self-maintenance and emulation of legacy products. Comprehensive solutions of the highest standards: that's our philosophy.



BY BONNIE BAKER

Designing with temperature sensors, part two: thermistors

hermistors, which range in price from 10 cents to approximately \$25, find use in applications from automotive monitoring and exhaust-emissions control to ice detection, skin sensors, blood and urine analyzers, home appliances, mobile phones, base-station laser drives, and battery-pack charging. Thermistors are either NTC (negative temperature coefficient) or PTC (positive temperature coefficient). NTC thermistors best suit precision temperature measurement, and PTC devices best suit switching applications. This column focuses on NTC devices.

The most prevalent NTC-thermistor configuration uses the resistance-versus-temperature characteristics of the device. The thermistor must operate in a "zero-power" condition, which implies that current or voltage excitation to the thermistor does not induce self-heating. Figure 1 shows the temperature response of a 10-k Ω NTC thermistor. Note the nonlinearity.

Typically, the 25°C rating for thermistors is 1 k Ω to 10 M Ω . Because thermistors are resistive elements, they require current excitation from a voltage or a current reference. Although thermistors have better linearity than that of thermocouples, they still require linearization in most temperature-sensing circuits.

An empirical third-order polynomial, using the Steinhart-Hart thermistor equation (Reference 1), or a look-up table can correct the nonlinear response of the thermistor in soft-

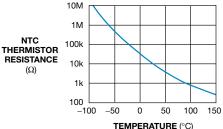
ware. The Steinhart-Hart equation provides approximately $\pm 0.1^{\circ}\text{C}$ accuracy over the full temperature range of the thermistor. In the **equation**, $\ln R_T = B_0 + B_1/T + B_3/T^3$, T is the temperature

Figure 1 The temperature response of a 10-k Ω NTC thermistor is nonlinear.

of the thermistor in kelvins; B_0 , B_1 , and B_3 are constants that the thermistor manufacturer provides; and R_T is the thermocouple resistance at T.

If you use these techniques to determine temperature, the nonlinearity of the thermistor still produces a nonlinear voltage output with a current-source excitation. The differential resistance for a 10°C change at high temperature is significantly smaller than the resistance at low temperatures. You can address this issue by using a high-resolution ADC, but you will lose some bits. An alternative is to implement linearization with the analog hardware.

A simple approach to a first-level analog linearization of the thermistor output is to use the circuit in **Figure 2**. The thermistor is in series with a standard, 1%-tolerant, metal-film resistor, and the temperature response and linearity of the system show that



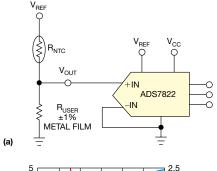
it responds to temperature in a linear manner over a limited temperature range. The linearization resistor's value, R_{USER}, should equal the magnitude of the thermistor at the midpoint of the temperature range of interest, creating a response in which the resistive network is at its steepest at this midpoint. If your design requires high precision, this range is typically ±25°C at approximately the midpoint temperature.

The circuit in **Figure 2** uses an ADS7822 from Texas Instruments to sense the voltage output (V_{OUT}) of the series configuration of the thermistor (R_{NTC}) and the series resistor. If the ADS7822 has low acquisition speed, the input circuitry to the converter will settle before conversion.

Read part one of this series, on sensor types, at http://bit.ly/rpSnOp.EDN

REFERENCE

Steinhart, JS, and Stan R Hart, Deep Sea Research, Volume 15, Elsevier, 1968.



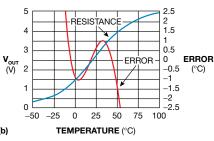


Figure 2 This circuit provides a simple approach to a first-level analog linearization of the thermistor output (a). In series with a standard, 1%-tolerant, metal-film resistor, the thermistor has a temperature response and linearity showing that it responds to temperature in a linear manner over a limited temperature range (b).

Rohde & Schwarz



Rohde & Schwarz is a global leader in test and measurement, broadcasting, secure communications, radiomonitoring and radiolocation. We create the instruments that help you build tomorrow's technology today. Our latest innovation: the most accurate signal and spectrum analyzer ever built. Meet the R&S°FSW.

Rohde & Schwarz. **Create the future**. www.rohde-schwarz.com/ad/fsw/edn



PRY FURTHER AT EDN.COM

+ Go to www.edn.com/pryingeyes for more Prying Eyes write-ups.

Evaluate your application's energy-harvesting vibrational profile with a Slam Stick

> idé Technology's energy-harvesting devices rely on resonant harvesting. To extract the maximum available vibrational energy from their environment, the harvesters must be "tuned" to match the vibration. To know whether your application is suitable for this type of harvesting, you must determine the vibrational profile by using an accelerometer. To ease the task of profiling, Midé designed the Slam Stick—a data logger that measures acceleration in all three axes—with the form factor of the familiar USB (Universal Serial Bus) stick.

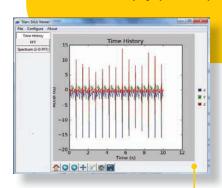
> > Microchip PIC18F25J50 microcontroller, which integrates a full-speed USB 2.0 transceiver and a 10-bit, 10-channel ADC. The Slam Stick also uses Analog Devices' three-axis ADXL345 accelerometer. According to Tim Gipson, a design engineer at Midé, using a high-Q resonating piezoelectronic beam to harvest energy requires accurate knowledge of the vibration frequency, ideally within 1 to 2 Hz. The ADXL345 internally generates its own sampling clock; however, this clock frequency can vary from part to part. In response, Midé runs an accurate, 32-kHz oscillator along with the accelerometer to determine its actual sampling rate and stores a correction factor in the recording file, giving

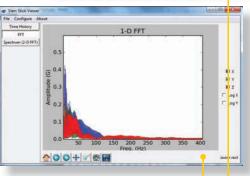
fractional-hertz accuracy.

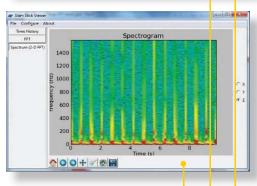
The Slam Stick uses an 8-bit

The reverse side of the Slam Stick shows its lithium-polymer battery. The device charges in one to two hours after you plug it into a USB port. A green LED indicates when it's ready to go. The company evaluated some thin-form-factor supercapacitors early in the design, but the lower self-discharge and flatter discharge curve of the lithiumpolymer battery keep the design small and simple.









The Slam Stick works with its open-source analysis software. The screen on the top shows the recorded g force versus time over the Stick's default 10-sec recording period. The middle screen shows an expanded view of an FFT (fast Fourier transform), which converts the amplitude versus time of the data to frequency versus time. The bottom screen shows a spectrogram of the shoe strike.

The software doesn't currently tell you how much energy is being generated because the amount of energy available for harvesting depends on several factors beyond the frequency and amplitude. For example, the same piezoelectric beam with a small proof mass at the end versus a large proof mass in the center might tune to the same frequency but have different power outputs in the same environment.



स्या आप MATLAB बोलते हैं?

Over one million people around the world speak MATLAB.
Engineers and scientists in every field from aerospace and semiconductors to biotech, financial services, and earth and ocean sciences use it to express their ideas.
Do you speak MATLAB?



Saturn's northern latitudes and the moon Mimas. Image from the Cassini-Huygens mission.

Related article at mathworks.com/ltd

European Space Agency ©2011 The MathWorks.

• MATLAB[®]

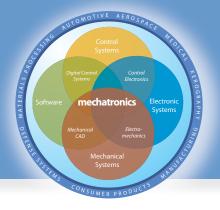








MECHATRONICS FRESH IDEAS ON INTEGRATING MECHANICAL SYSTEMS, ELECTRONICS, CONTROL SYSTEMS AND SOFTWARF IN DESIGN



No fighting

In life and in mechanical design, keep the peace.

ost engineers have taken a course on the design of machines and machine elements. These courses, however, often overlook the insight that expert machine designers have gleaned from years of practice. Guiding principles—for example, keep complexity intrinsic, keep functions independent, improve designs with self-help, and plan load paths in assemblies—are not well-publicized. One of the most important guiding principles is exact-constraint design, and references 1 and 2 provide material on that topic, with Reference 2 serving as the source for much of this column.

Precision machines are essential elements of an industrial society. A precision machine is an integrated system that relies on the attributes of one component to augment the weaknesses of another component. Characteristic to all precision systems is the high level of determinacy they require. Predictable and reproducible behavior is a key quality that only carefully designed, robust mechanics and control systems can achieve. To achieve excellent and predictable behavior, the mechanisms require, among other things, exact constraint—just enough constraint to define a position or motion. Unlike overconstrained designs, exactly constrained designs boast a repeatable position, easy assembly, and robustness to wear and environment. They have no binding, no play, no internal stress, and no loose-tolerance parts.

A 3-D object has six degrees of freedom—the number of independent coordinates necessary to describe a system's

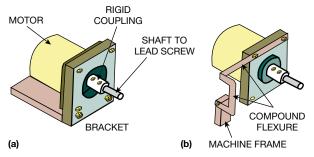


Figure 1 A first design shows a cyclic error in linear motion (a). A constraint analysis shows that the design is overconstrained. The compound flexure eliminates the problem by eliminating the need for an expensive lead screw, accurate machining, and assembly steps (b).

motion—three translations and three rotations. Selectively constrain these degrees of freedom to obtain the desired motion or structure. If you rigidly constrain a component at more places than necessary—by, for example, placing three bearings on one shaft—these places will "fight" with each other.

The design of high-quality precision machines depends primarily on an engineer's ability to predict how the machine will perform before he builds it. The most important factors affecting the quality of a machine are its accuracy; its precision, or repeatability; and the resolution of its components and the manner in which they are combined. Accuracy is the ability to tell the truth, precision is the



Kevin C Craig, PhD, is the Robert C Greenheck chairman in engineering design and a professor of mechanical engineering at Marquette University's College of Engineering. For more mechatronic news, visit mechatronics zone.com.

ability to tell the same story over and over again, and resolution is how much detail the story has. Designing a machine that has good accuracy, precision, and resolution is not a black art.

Consider the use of linear drives for scanning. They often comprise a motor attached to a lead screw, which in turn drives the scanning carriage. A first design shows a cyclic error in linear motion (Figure 1a). Trying more accurate machining, better part alignment, and a more expensive lead screw yields no success. A constraint analysis shows that the design is overconstrained. The motor attaches rigidly to the lead screw, so the motor requires only one constraint: to prevent the rotation of its housing. The compound flexure eliminates the problem by eliminating the need for an expensive lead screw, accurate machining, and assembly steps (Figure 1b).

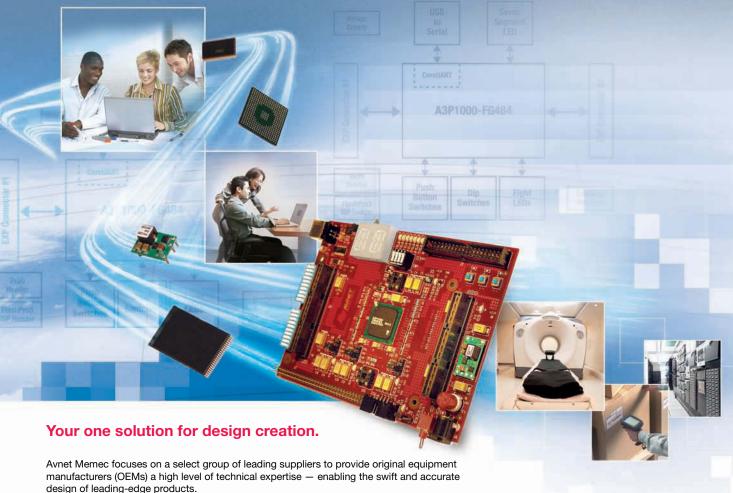
Understanding how to transform basic physical principles into working concepts with predictable behavior is the key to achieving high accuracy, high speed, and high reliability. **EDN**

REFERENCES

- Blanding, Douglass L, Exact Constraint: Machine Design using Kinematic Principles, ASME Press, 1999.
- Skakoon, James G, *The Elements of Mechanical Design*, ASME Press, 2008, ISBN: 978-0-7918-0267-0.

28 EDN | OCTOBER 20, 2011 [www.edn.com]

Accelerating the **Speed of Design**.



design of leading-edge products.

With factory trained and certified support, Avnet Memec specialists offer a level of technical depth unmatched in the industry. With easy access to our industry experts, your projects move forward with greater velocity, driven by in-depth technical expertise. That translates into faster time to market for you, with greater ease and confidence. From Design to Delivery.™ Avnet is ranked Best-in-Class* for online seminars, design & engineering services and knowledgeable application engineers - proof that we consistently deliver:

- > Proactive engineering support
- > Factory certified FAEs

Accelerate Time to Market.™

Visit the Avnet Design Resource Center™ at: www.em.avnet.com/drc





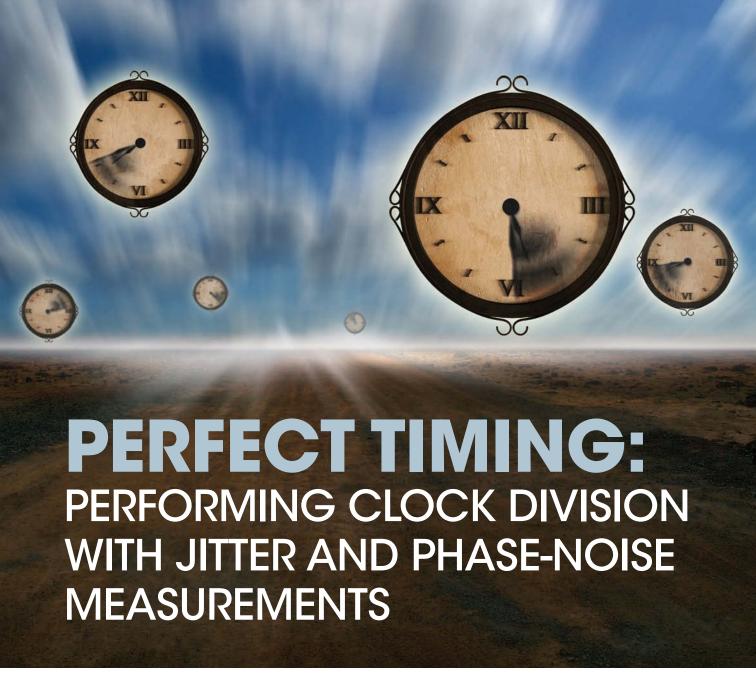
Accelerating Your Success ***

1 800 332 8638 www.avnetexpress.com







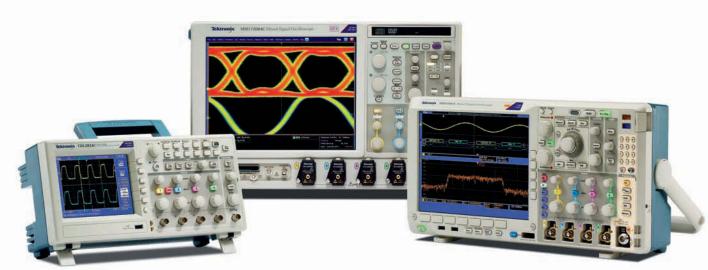


AS CLOCK SPEEDS AND COMMUNICATION CHANNELS OPERATE AT EVER-HIGHER FREQUENCIES, ACCURATE JITTER AND PHASE-NOISE MEASUREMENTS BECOME MORE IMPORTANT, EVEN AS THEY BECOME MORE DIFFICULT AND EXPENSIVE TO MANAGE. SOME PRACTICAL POINTERS AND OBSERVATIONS ASSIST IN HANDLING THESE PROBLEMS.

BY HOWELL MITCHELL • SILICON LABORATORIES

hen measuring ultra-low-jitter devices and equipment, engineers must constantly ask whether the measurement values are from the DUT (device under test) or from the test equipment. Engineers are also always looking for methods of expanding the reach of the equipment at hand. This article describes some practical ways to handle situations in which clock signals have been divided down from higher-frequency VCOs (voltage-controlled oscillators).

Oscilloscopes Don't Change the World. Engineers Do.



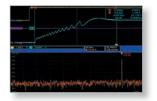
Performance Analysis - DC to 80 GHz

Basic Visualization - 40 to 500 MHz

Bench Debug - 100 MHz to 1 GHz

No wonder so many trust Tektronix oscilloscopes, the world's standard for innovation.

Tektronix offers the broadest portfolio of oscilloscopes to debug and test tomorrow's designs, today. Start with Tektronix Basic oscilloscopes. Fast, familiar and affordable, they're what you know and trust. Our Bench oscilloscopes—including the world's first Mixed Domain Oscilloscope—provide next-level productivity, with the feature-rich tools you need to debug today's complex mixed signal designs. And for those who demand the industry's best signal fidelity, verification and characterization capabilities, our Performance oscilloscopes help you shorten your design cycles.



See why so many engineers worldwide rely on Tektronix oscilloscopes.

www.tektronix.com/worldstandard



Most modern equipment that measures jitter can be placed into one of two broad categories: time domain or frequency domain. Time-domain equipment typically comes in the form of a high-speed digital oscilloscope with high single-shot sampling bandwidth. Frequency-domain equipment usually comes in the form of a spectrum analyzer, a spectrum analyzer with phase-noise measurement capability, or a phase-noise analyzer. Each of these two categories of equipment has its own set of advantages and disadvantages. However, both measure the same phenomena, albeit with different approaches.

Peak cycle-to-cycle jitter is the maximum difference between consecutive, adjacent clock periods over a fixed number of cycles—typically, 1000 or 10,000. It is used whenever there is a need to limit the size of a sudden jump in frequency. For example, when driving a PLL (phase-locked loop), you may want to limit the size of an instantaneous change in frequency to ensure that downstream PLLs remain in lock (Reference 1 and Figure 1).

The peak-to-peak period jitter is the difference between the largest clock period and the smallest clock period for all clock periods within an observation window—again, typically 1000 or 10,000 cycles (Figure 2). It is a useful specification for guaranteeing the setupand-hold time of flip-flops in digital systems. "Peak-to-peak" refers to the difference between the smallest and the largest sampled period value during a measurement.

TIE (time-interval-error) jitter, or accumulated jitter—also known as phase jitter—is the actual deviation from the ideal clock period over all clock periods (**Figure 3**). It includes jit-

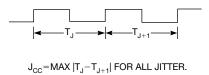


Figure 1 When driving a PLL (phase-locked loop), you may want to limit the size of an instantaneous change in frequency to ensure that downstream PLLs remain in lock.

AT A GLANCE

- Time-domain equipment is better than frequency-domain systems at measuring data-dependent jitter, making it useful for high-speed serial links that use SERDES (serializer/ deserializer) technology.
- High-quality frequency-domain instruments have lower noise floors than their time-domain counterparts, making frequency-domain units the instruments of choice for ultra-low-phase-noise clock-signal measurements that are free of data-dependent jitter.
- An instrument's noise floor can become the limiting factor of a measurement of phase noise of very-low-jitter clocks at low clock frequencies.

ter at all jitter-modulation frequencies and commonly finds use in WAN (wide-area-network) timing applications, such as SONET (synchronous optical network), synchronous Ethernet, and OTN (optical-transport networking).

You can create various types of statistics, such as rms (root-mean-square), peak-to-peak, cycle-to-cycle, period, and TIE jitter, although some are more

commonly used than others. Whenever peak-to-peak statistics are used, the number of samples taken must be large enough to produce confidence in the measurement. Such measurements typically include 1000 to 10,000 samples.

Time-domain equipment can directly measure peak-to-peak, cycle-to-cycle, period, and TIE jitter. This measurement approach permits the measurement of jitter for low-frequency clock, or carrier, signals. By employing FFTs (fast Fourier transforms), digital filters, and other techniques to postprocess the data, you can integrate the phase-noise value over a band of frequencies to generate rms-phase-jitter values. Time-domain equipment is better than frequencydomain systems at measuring datadependent jitter, making it useful for high-speed serial links that use SERDES (serializer/deserializer) technology.

Frequency-domain equipment cannot directly measure peak-to-peak, cycle-to-cycle, or period jitter; its native ability is to measure the rms power of a signal in a given frequency band. Frequency-domain equipment is also awkward for measuring data-dependent jitter. However, high-quality frequency-domain instruments have lower noise floors than their time-domain coun-



Figure 2 The peak-to-peak period jitter is the difference between the largest clock period and the smallest clock period for all clock periods within an observation window—typically 1000 or 10,000 cycles.

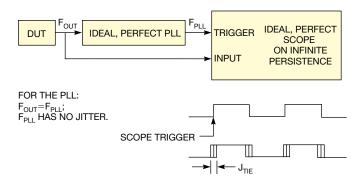


Figure 3 TIE jitter is the actual deviation from the ideal clock period over all clock periods.

terparts, making frequency-domain units the instruments of choice for ultra-low-phase-noise clock-signal measurements that are free of data-dependent jitter (Table 1).

Because this article focuses on the measurement of lowjitter clock signals, it omits further discussion of time-domain equipment except to mention that you can use various mathematical-estimation and -translation approaches to go from one type of jitter measurement to another. For example, it is possible to use a crest factor and a desired BER (bit-error rate) to go back and forth between peak-to-peak and rms jitter. Another example is using an FFT of time-domain data to provide frequency-domain information and filtering. However, most of these techniques rely on mathematical models, which may be good approximations in most situations but have limitations. As such, you should use them only carefully.

One issue that bears further investigation is the effect of clock, or carrier, frequency on the jitter measurement. It is intuitive that a clock signal divided down by an ideal divider will have the same clock edge jitter at both its input and output (**Figure 4**). In the **figure**, the top jittered signal with frequency $F_{\rm O}$ is divided by two using a perfect divider to produce a clock frequency of $F_{\rm O}$ /2. Both clock signals have the same jitter, $J_{\rm O}$. Note that the jitter energy of the lower clock signal is half that of the higher clock signal because there are half as many edges in a given interval of time.

The intuition that J_{\odot} is the same for the two clock signals is for the most part true, despite the fact that the phase noise of a clock signal that is divided by two will be 6 dB lower than the phase noise of the original clock signal. Note that, for division by two, 6 dB=20×log2 (Reference 2).

The following example illustrates the effect of division by powers of two for both phase noise and jitter. These measurements employ a Silicon Laboratories Si5324 PLL device (Figure 5). Note that the high-speed VCO resynchronizes the output clock, regardless of the final output frequency, meaning that the edge shape and placement should be the

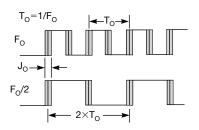


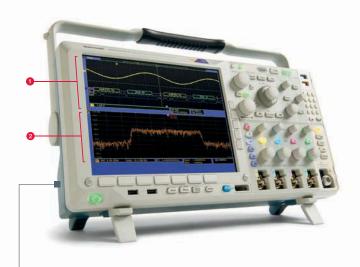
Figure 4 It is intuitive that an ideal divider divides down a clock signal that has the same clock-edge jitter after the divider as it has before the divider.

TABLE 1 DIFFERENCES IN TIME- VERSUS FREQUENCY-DOMAIN INSTRUMENTS

	Time domain	Frequency domain
Native measurements	Peak-to-peak, cycle-to-cycle, and period jitter	Phase noise, rms phase jitter, jitter-frequency information
Advantages	Good with low- frequency clocks and data-dependent jitter	Lower noise floor, easy detection of spurs versus random jitter



The World's First Mixed Domain Oscilloscope



MDO4000 Mixed Domain Oscilloscope

1 Time Domain 2 Frequency Domain

4 analog channels

500 MHz and 1 GHz bandwidth models

16 digital channels

■ 1 RF channel

- o 50 kHz-3 GHz and 50 kHz-6 GHz frequency range models
- Ultra-wide capture bandwidth up to 3 GHz
- Unique RF analysis tools: automated markers, spectrogram display, RF vs. time traces, advanced RF triggers
- Parallel bus triggering and analysis, included standard
- Serial bus triggering and analysis options
- Built on the award-winning MSO4000B mixed signal oscilloscope platform

Introducing the MDO4000 Series from Tektronix, the revolutionary oscilloscope with a built-in spectrum analyzer. It's more than just

a new scope—it will transform the way you test. Capture time-correlated analog, digital and RF signals for a complete system view of your device. See both time and frequency domains in one glance. View the RF spectrum at any point in time to see how it changes. Quickly and efficiently solve the most complicated design issues—with an oscilloscope as integrated as your designs. Two domains. One remarkable scope. Only from Tektronix.

Take a look at how we've transformed testing: See the scope in action, analyze the specs and learn more at **www.tektronix.com/revolutionary**.

Tektronix

same for all possible divider values. The only difference should be that fewer clock edges occur during a given time interval. Although some retiming noise remains, the noise is the same for all of the divisor values (**Figure 6**).

The six curves in the **figure** are essentially the same but with a verti-

cal separation of 6 dBc/Hz. The 6-dB separation is relatively constant over all offset frequencies and divisor values, with one or two exceptions. On the right side of the plot, in which the offset from the clock, or carrier, is at its largest, the relative vertical offsets between the curves are compressed. The compres-

sion increases as the clock frequency decreases. This compression becomes more pronounced as the clock frequency and the phase-noise-curve values decrease. The compression occurs because the noise floor of the Agilent Technologies model E5052B signalsource analyzer nears the value of the phase noise, or jitter generation, of the Si5324 IC. The noise floor is an issue only because of the combined effect of the ultra-low jitter of the Si5324 and the low carrier frequency. Table 2 lists the corresponding jitter values for each of the six plots with the jitter integrated from 100 Hz to 20 MHz and all jitter values in femtoseconds rms.

Notice that the jitter increases slightly as the output frequency decreases—evidence that the output jitter is relatively constant despite the fact that 6 dB separates the phase-noise curves from one another. The rate at which the litter increases becomes more pronounced at the lowest output frequencies. Let's examine the two sources of the increased rms-phase-noise values:

instrument noise floor and aliasing.

NOISE FLOOR, PHASE NOISE

The instrument's noise floor can become the limiting factor of a measurement of phase noise of very-low-jitter clocks at low clock frequencies. At some point, you are measuring your equipment, not the DUT. Even though the phase-noise curves become monotonically smaller as the clock frequency decreases, the rms edge jitter remains almost constant because the phase-noise integration uses the clock period to scale the rmsiitter values.

To illustrate how this scenario occurs, consider the process of phasenoise integration to produce an rmsjitter value. Most modern phase-noise equipment produces a file that has two columns—typically, a CSV (commaseparated-value) file. One of the two columns lists the frequency offset from the clock, or carrier, frequency in hertz. The other column lists the phase-noise values at that offset frequency in decibels referenced to the carrier per hertz. Thus, the columns contain data-point pairs that describe the phase noise at a given offset from the clock frequency. Integration involves summing the area under the curve for all of the frequency-offset points after converting the

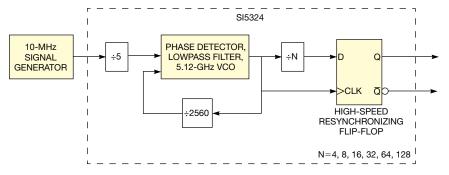


Figure 5 The measurements employ a Silicon Laboratories Si5324 PLL device.

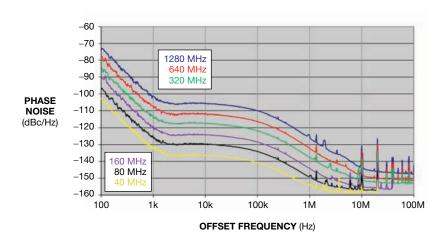


Figure 6 The high-speed VCO resynchronizes the output clock, regardless of the final output frequency, meaning that the edge shape and placement should be the same for all possible divisor values. The only difference should be that fewer clock edges occur during a given time interval.

TABLE 2 RMS-JITTER VALUES FOR DIFFERENT VALUES **OF DIVISION Jitter** Output frequency Color Divisor (MHz) (fsec rms) Blue 1280 Four 441 Red 640 447 Eiaht Green 16 320 461 **Purple** 32 160 463 Black 80 477 64 Yellow 128 40 523

34 EDN | OCTOBER 20, 2011 [www.edn.com] decibels-referenced-to-the-carrier-per-hertz values to linear values using the following **equation**: Linear values=10^{(dBc/Hz)/10}.

The equation for the area of a trapezoid in **Figure 7** is used to find the area described by two adjacent data-point pairs. You find the area under the curve by summing the area of all of the trapezoids. The final rms-jitter value is determined by scaling the result by two factors: The value $\sqrt{2}$ comes from the fact that the data was taken as one sideband; however, the rms jitter is assumed to be dual sideband. It is usually safe to assume that the two sidebands of the phase noise are symmetric about the clock frequency. In this case, it is even safer because a limiting amp suppresses AM (amplitude modulation) and passes FM (frequency modulation) to ensure symmetric sidebands (**Figure 8**).

The other scaling factor converts the area sum so that it is no longer in UIs (unit intervals) but in units of time. This factor keeps the rms edge jitter's values relatively constant, whereas the phase-noise values change. The equation for rms jitter is expressed as follows:

rms jitter=
$$\frac{\sqrt{2}}{2\pi F_{C}}\sum_{i}\frac{(F_{i+1}-F_{i})\times\left(\frac{(N_{i}+1)}{10}+\frac{(N_{i})}{10}+\frac{(N_{i})}{10}\right)}{2}$$
,

where F_C is the clock frequency, N_i is the phase noise in decibels referenced to the carrier per hertz for the ith entry, and F_i is the offset frequency for the ith entry.

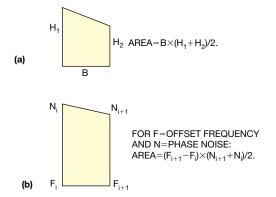


Figure 7 You find the area under the curve by summing the area of all of the trapezoids. You determine the final rms-jitter value by scaling the result by two factors.

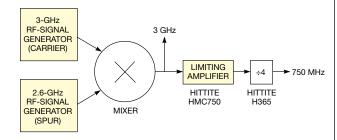


Figure 8 A limiting amp suppresses AM and passes FM to ensure symmetric sidebands.

The World's Most Accurate Oscilloscope.

For engineers who demand performance without compromise.

Discover your real signal detail with the industry's highest waveform capture capability so you can perform accurate in-depth analysis of your high-speed signals. Providing exceptional signal acquisition performance and analysis capability, the DPO70000 Series is the world's most accurate oscilloscope. Design without compromise.



- Up to 33 GHz and 100 GS/s, less than 9 ps rise time
- \circ \geq 5.5 effective bits @ 33 GHz
- Visual Trigger makes the identification of complex events quick and easy
- 16 logic channels with 80 ps timing resolution (MSO models only)
- Automate waveform collection and analysis using MATLAB® or LabVIEW®
- Over 30 customizable application-specific software analysis packages for PCle, SATA, USB and more

Get detailed specifications, virtual demos and more at: **www.tektronix.com/reliability**



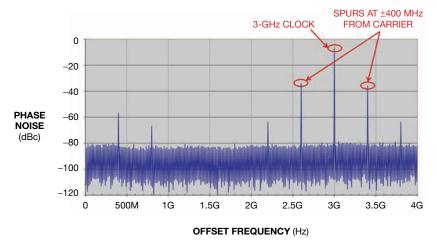


Figure 9 Symmetrical spurs occur at frequencies of 400 MHz above and below the 3-GHz clock frequency.

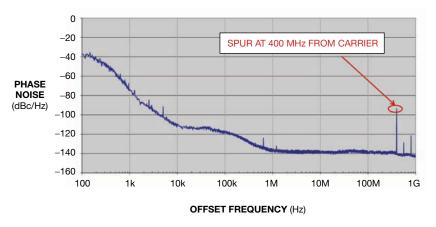


Figure 10 When the spectrum shows two equal sidebands, the phase-noise plot of the same signal combines their effect into one spur 400 MHz from the 3-GHz carrier. A divide-by-four circuit then divides down the 3-GHz signal to produce 750 MHz.

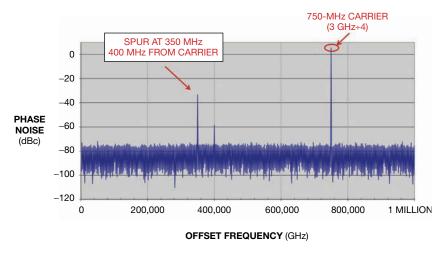


Figure 11 The spurs at 2.6 and 3.4 GHz alias down to a sideband spur at 350 MHz.

ALIASING

Aliasing is another cause of increasing rms-jitter values with decreasing clock frequency. For every division of two, the upper half of a phase-noise plot aliases down into the new lower-clockfrequency phase plot. Because phase noise is usually higher close to the clock or carrier frequency and drops off as the offset from the clock frequency increases, relatively little phase noise aliases down. However, when dividing by large numbers, the effect becomes cumulative and significant. For example, the difference between the 1280- and the 640-MHz curves in Figure 1 is a constant 6 dB across the entire plot. As a result, you would expect that the increased rms-jitter values for the two curves in Table 2 are due entirely to aliasing and not to the instrument's noise floor.

The spectra and phase-noise plots in Figures 9 through 13 illustrate aliasing. The signals in these examples use AM to illustrate aliasing and are not what would be expected in a typical application. Figures 9 and 10 show the spectra and phase-noise plots for the 3-GHz signal. The plots show symmetrical spurs at frequencies of 400 MHz above and below the 3-GHz clock frequency. When the spectrum shows two equal sidebands, the phase-noise plot of the same signal combines their effect into one spur 400 MHz from the 3-GHz carrier. A divideby-four circuit then divides down the 3-GHz signal to produce 750 MHz.

Figures 11 and 12 show the spectra and phase-noise plots of the 750-MHz signal from the divide-by-four circuit. As a result of the division by four, the spurs at 2.6 and 3.4 GHz alias down to a sideband spur at 350 MHz. Note that 350 MHz is a frequency value that is the same 400 MHz from the 750-MHz carrier as 2.6 GHz is from the 3-GHz carrier. To further illustrate the aliasing, the 750-MHz signal is again divided down to 375 MHz. The 25-MHz spur in Figure 13 is an alias of the spur at 350 MHz in Figure 11; that is, 25 MHz=375 MHz-350 MHz.

As you can see, the instrumentation's noise floor can become a limiting factor when measuring low-jitter clocks with low-frequency values. When a higher-frequency clock divides down the clock being measured, you can lower the value of the divider so that the measurement takes place at a higher frequency.

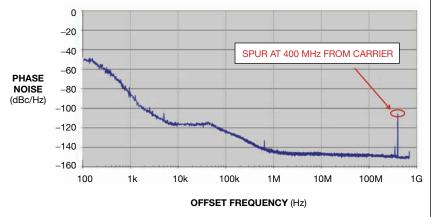


Figure 12 The 350-MHz frequency value is the same 400 MHz from the 750-MHz carrier as 2.6 GHz is from the 3-GHz carrier.

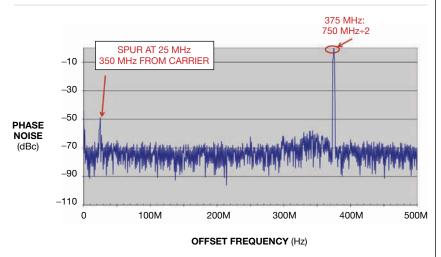


Figure 13 The 25-MHz spur is an alias of the spur at 350 MHz in Figure 11.

However, this commonly used technique removes the jitter contribution from higher-frequency jitter components that would have been aliased down by the division. Although the resulting rms-jitter values may be artificially lower, this approach is acceptable in applications in which the phase noise that is far off of the corner is relatively small. When measuring low-frequency clocks with appropriately high amounts of jitter, use time-domain equipment because the measurement can be made at the actual desired output frequency, no matter how low the clock frequency may be. EDN

ACKNOWLEDGMENT

This article originally appeared on EDN's sister site, Test & Measurement Designline, http://bit.ly/pCHBRD.

REFERENCES

Li, Mike Peng, Jitter, Noise, and

Signal Integrity at High-Speed, Prentice Hall, 2008, ISBN: 0-13-242961-6.

Gardner, Floyd M, Phaselock Techniques, Third Edition, John Wiley & Sons, 2005, 0-471-43063-3.

AUTHOR'S BIOGRAPHY



Howell Mitchell is a staff applications engineer at Silicon Laboratories, where he is responsible for product support for a family of jitter-attenuating PLL-based

timing devices. Before joining Silicon Labs, he was a principal engineer at MagiQ Technologies, where he worked in quantum-key distribution. Mitchell holds five patents in phase modulation and quantum-key distribution. He received a bachelor's degree in physics from Bucknell University (Lewisburg, PA) and a master's degree in engineering from Northeastern University (Boston).

Pickering

Quality Reed Relays

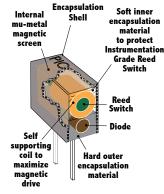
Need Instrument Grade Reed Relays For Ultra-High Density Applications? Look No Further Than Our Series 117

The Pickering Series 117 is a range of Single-in-Line relays intended for very high density applications such as A.T.E. switching matrices or multiplexers.

They are available with either 1 or 2 Form A (energize to make) switches and are the ideal choice for ultra-high density applications.



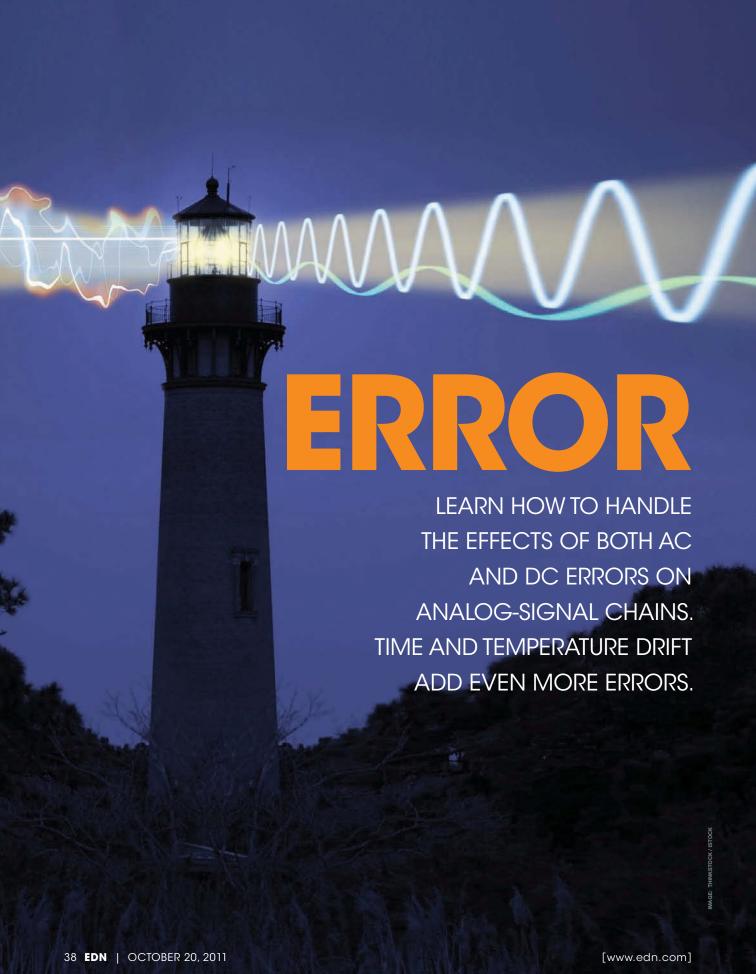
Only Pickering has SoftCenter™ Technology



Pickering Reed Relays are encapsulated using a soft inner material to protect the reed switch capsule. The very hard compounds used by most other manufacturers can cause stresses that can potentially damage the reed switch and degrade contact resistance stability and life expectation. Go to www.pickeringrelay.com to find out more....

Free samples available on request.





BUDGETS

KEEP YOUR ANALOG-SIGNAL PATH

HONEST

BY PAUL RAKO • TECHNICAL EDITOR

o deal with errors in your design's analog-signal chain, you must understand their sources in attenuators, amplifiers, multiplexers, references, and ADCs. Although Monte Carlo Spice simulations can help you handle component tolerances, keep in mind that resistor tolerances can create dc errors and that capacitors and inductor tolerances can create ac errors. The stray capacitance and inductance on PCBs (printed-circuit boards) also create ac errors. Once you establish the dc and ac errors due to component tolerances, you can examine the dc and ac errors that the ICs in the signal path cause. You can then calculate and track all of the errors with a spreadsheet to ensure that your system will meet the required specifications (tables 1 and 2).

[www.edn.com] OCTOBER 20, 2011 | EDN 39

Some programmers' claims that you can calibrate out all errors in software may lull you into a false sense of security regarding the errors in your design. However, dc analysis ensures that your ADC receives the required signal at its full dynamic range without clipping. A 10-bit converter has 1024 steps in its output code, so you might think it would be ideal for a 0.1%-accurate system because it has a range better than 1000-to-1. However, dc errors in the signal chain can put 100 counts of offset into the signal at the ADC, so you cannot achieve 0.1% accuracy no matter how much software correction you do. If the 100-count offset is positive, the ADC provides digital outputs only from 100 to 1024—not the full range of more than 1000 counts—so this system cannot achieve 0.1% accuracy. This situation is true even if software reduces the gain so that the ADC input does not saturate at its most positive level. Software can reduce the gain of the signal by 100 counts to compensate for

AT A GLANCE

- Every component in the signal chain contributes ac errors, do errors, or both.
- You must examine, analyze, and tabulate the errors in the signal chain so that the trade-offs you make ultimately yield a feasible design.
- Tiny signals and fast signals need special attention.
- You can use a spreadsheet to calculate errors.

the positive offset, but the signal still does not have a dynamic range of the full 10 bits.

Every component in the signal chain contributes ac errors, dc errors, or both (Figure 1). Other errors are due to drift, which most commonly refers to specification changes over temperature. Time drift, which contributes ac errors, refers to the changes in spec as a component

ages, but the drift is so slow that engineers don't consider the errors to be normal ac errors. Electrical noise, which is inherent in the atomic vibrations due to temperature and can be a function of the quantum mechanics in a semiconductor device, also causes errors. As with so many other gray areas in analog design, you might think of time drift as low-frequency noise.

Errors, drift, and noise all conspire to make your analog-signal chain less accurate than you might hope. For this reason, experienced analog engineers would not start with a 10-bit ADC to make a 0.1%-accurate system; they would instead start with a 12- or even a 14-bit converter to leave margin for all of the analog components that contribute to the total system error. Some application engineers who work for ADC groups maintain that the analog components feeding the converter should be transparent, so that they have no effect on the converter. This scenario is at best optimistic and at worst

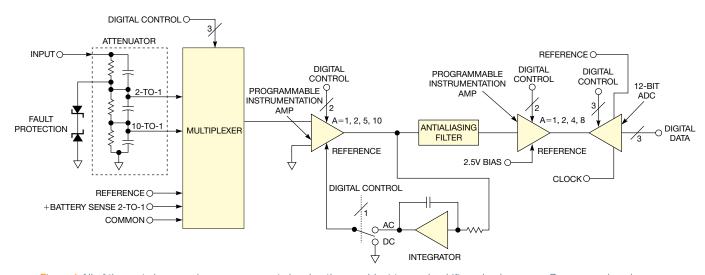
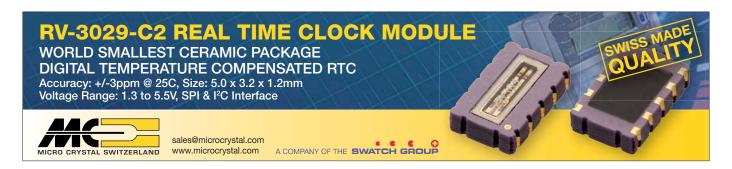


Figure 1 All of the parts in an analog-measurement signal path are subject to ac, dc, drift, and noise errors. Power-supply noise can also creep into the signal chain and ruin your measurements.



40 **EDN** | OCTOBER 20, 2011 [www.edn.com]

More engineers choose ADI data converters over the next 8 suppliers combined.



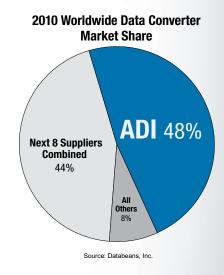
More products. More performance. More design support. More education.

With so many complex design problems relying on data converters to define system performance, and so many data converter suppliers to choose from, you might think it's remarkable that so many engineers agree on their choice: Analog Devices. As the world's #1 data converter supplier, ADI is your source for 1500+ converter products, all thoroughly and conservatively specified, and backed with more tools, training, and design support than any other supplier—by far. See why more engineers turn to ADI for answers to their toughest challenges. Explore products, customer stories, and design resources at www.analog.com/ConverterLeader.

Leading Converter Innovations

- AD9467: 16-Bit, 250 MSPS, IF Sampling ADC
 Provides outstanding SFDR performance over wide bandwidths; multiple on-chip functions and adjustability features for ease of use.
- AD5624R: Quad, 12-Bit SPI nanoDAC®
 Offers 12-bit accuracy (1 LSB INL) and on-chip
 1.25 V or 2.5 V 5 ppm/°C reference, all in a 10-lead
 MSOP and 3 mm × 3 mm 10-lead LFCSP.
- AD7626: 16-Bit, 10 MSPS PulSAR® ADC
 Delivers an unequaled combination of effective
 resolution and speed, without compromising ac or
 dc performance, while reducing size and power.
- AD9122: Dual, 16-bit, 1200 MSPS,
 TxDAC+® Transmit DAC
 Enables multicarrier generation up to the Nyquist
 frequency and includes features optimized for direct
 conversion transmit applications.







Circuits from the **Lab** Reference Circuits

Lower your design risk and speed time to market with ADI lab tested reference circuits. Use a QR reader on your smartphone to watch video.



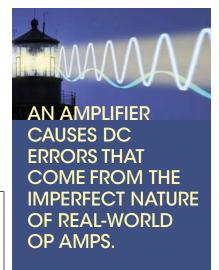
impossible. Like all things analog, it involves a trade-off. Perhaps you can use a cheaper ADC and better analog components to feed the converter. Then again, it may be better to use a more expensive converter and cheaper analog components. If you are lucky, you can use an inexpensive converter and inexpensive components and calibrate out all the errors with software. In any event, you must examine, analyze, and tabulate the errors in the signal chain so

that the trade-offs you make ultimately yield a feasible design.

Component tolerances are fundamental sources of errors. You must analyze and understand how component tolerances affect your input attenuator and other circuits (see **sidebar** "Component tolerances").

FIRST ANALYZE DC ERRORS

Once you understand the dc and ac errors that the input attenuator con-



tributes, you can look at the rest of the signal chain. The input multiplexer can contribute dc errors due to the small on-resistance of the internal semiconductor switches in the part. The onresistance appears in series with the input resistor to the amplifier, creating an error term. The leakage from the multiplexer channels that are off also add a dc error. The multiplexer and the loading on the input attenuator cause errors, so you must tailor the input impedance of the first amplifier to minimize these errors. The resistor values of the first amplifier can cause issues that create more errors.

An amplifier causes dc errors that come from the imperfect nature of real-world op amps (Figure 2). The resistor values are used to set the closed-loop noise gain, which multiplies the op amp's offset-voltage error that appears at the output (Reference 1). For noninverting-amplifier configurations, the noise gain equals the closed-loop gain. For inverting configurations, the noise gain equals the closed-loop gain plus one.

The bias current that enters or exits the input pins also creates an error. When you analyze the input bias error, remember that the op amp is in the circuit and is working. As a result, the input bias current reacts to the source resistor, but the op amp servos the voltage that the current creates to keep the input pins of the amplifier at the same voltage. The op amp maintains a constant voltage across the input resistor, so the output error due to input bias current is purely a function of the feedback resistance times the bias cur-



Is your scope lying to you? Find out. Rohde-Schwarz-scopes.com

If you're not using a new Rohde & Schwarz digital oscilloscope, your scope may not be giving you honest answers.



Try the industry's most accurate and reliable digital oscilloscope.



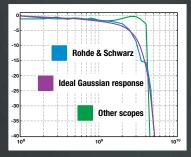
888-837-8772 www.rohde-schwarz-scopes.com





Scope Lie #1 Your digital scope's bandwidth

When it comes to small signal bandwidth, engineers need a gradual signal roll-off to avoid seeing a lot of ringing and overshoot in the time domain.



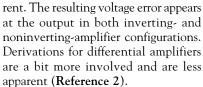
Today's digital scopes employ very sharp, high-order frequency responses that trade minimum sampling rates for maximum bandwidth. The result is high overshoot and ringing when measuring typical digital signals.

Try the scope that tells the truth by utilizing slow roll off to eliminate overshoot and ringing.

Discover how your digital scope may be misrepresenting results at

www.rohde-schwarz-scopes.com

888-837-8772



How accurately you scale a signal to your intended gain can also create a dc error. You can refer to published resources to see how a gain error occurs; the open-loop gain of any op amp is not infinite (Reference 3). The results of the analysis may also surprise you when you see how significantly large errors can creep into your design. You can derive the gain error as a function of the difference in the ratio, N, between the open- and the closed-loop gain, as the following equation shows:

$$\delta = 1 - \frac{N}{1 + N} = \frac{1}{1 + N}$$

Thus, if only a 20-dB difference exists between the open- and the

closed-loop gain, N equals 10, meaning that gain error is 9.1% (Reference 4). Your error spreadsheet should have a term for this error. Older parts, such as Texas Instrument's LM741 op amp, have minimum open-loop gains of only 10,000 over temperature. In this case, the IC designers provided some good specs at the expense of others. Your application's requirements determine which specs are most important.

Gain nonlinearity also causes measurement errors and is more difficult to characterize and incorporate in an error budget. If the manufacturer of the part you are using does not define gain nonlinearity, you may need to characterize a batch of parts (Figure 3 and Reference 5).

Using op amps in a noninverting arrangement can cause common-mode errors. The common-mode voltage appears on both input pins in common relative to the power-supply rails. Op amps create the least error when

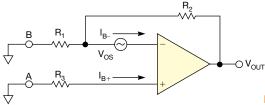
TABLE 1 SLOW- AND FAST-CHANNEL ERROR COUNTS				
	Slow channel (counts)	Fast channel (counts)		
Input attenuator	0	0		
Buffer amplifiers	0	0		
Multiplexer	0	0		
First PGA	4	4		
Filter	NA	NA		
Second PGA	0.2	0.2		
Level shift	4.1	0		
ADC	NA	NA		
Total	8.3	4.2		
Maximum allowed	28	28		
Margin	19.7	23.8		

TABLE 2 OFFSET ERROR					
Input voltage (V)	Attenuator accuracy (%)	Attenuator common-mode voltage (V)	Buffer amplifiers (%)	Multiplexers (%)	First PGA
100	0.01	0.2	0	0	0.1
50	0.01	0.2	0	0	0.1
20	0.01	0.2	0	0	0.1
10	0.008	0.16	0	0	0.1
5	0.008	0.16	0	0	0.1
2	0.008	0.16	0	0	0.1
1	0.008	0.16	0	0	0.1
0.5	0.008	0.16	0	0	0.1
0.2	0.008	0.16	0	0	0.1
0.1	0.008	0.16	0	0	0.1

the input pins are in the center of the power rails. As the input pins approach either rail, an error occurs in the output (Figure 4). "Think of it as a worsening of the offset voltage as you sweep the input pins toward either rail," says Paul Grohe, an amplifier-application engineer at Texas Instruments. That offset acts just like the inherent offset voltage: The noise gain multiplies it, and it appears at the output.

Although some manufacturers pub-

lish charts that show CMRR (common-mode-rejection ratio) as a function of common-mode input voltage (**Figure 5**), Linear Technology provides graphs for bias current versus common-mode voltage, according to Tim Regan, an amplifier-application manager at the company. These graphs show the effects of common-mode limits versus temperature. Rail-to-rail parts have a guaranteed CMRR with common-mode voltage all the way to either power



$$\begin{split} & \text{OFFSET (RTO)} = \text{V}_{\text{OS}} \Bigg[1 + \frac{R_2}{R_1} \Bigg] + \text{I}_{\text{B}+} \times \text{R}_3 \Bigg[1 + \frac{R_2}{R_1} \Bigg] - \text{I}_{\text{B}-} \times \text{R}_2. \\ & \text{OFFSET (RTI)} = \text{V}_{\text{OS}} + \text{I}_{\text{B}+} \times \text{R}_3 - \text{I}_{\text{B}-} \Bigg[\frac{R_1 \times R_2}{R_1 + R_2} \Bigg]. \end{split}$$

Figure 2 You can calculate offset errors referred to the output or the input pins of the amplifier (courtesy Analog Devices).

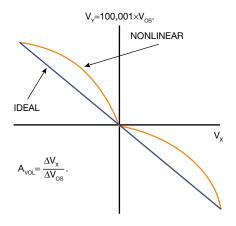
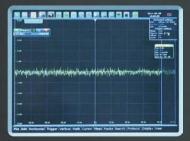


Figure 3 Gain nonlinearity shows up as an error between input V_Y and the amplifier's output, V_X (courtesy Analog Devices).

Filter (%)	Second PGA (%)	Level shifter (%)	Reference (%)	ADC (%)	Total (%)	Spec (%)
0.01	0.1	0	0.1	0.02	0.54	0.5
0.01	0.1	0	0.1	0.02	0.54	0.5
0.01	0.1	0	0.1	0.02	0.54	0.5
0.01	0.1	0	0.1	0.02	0.498	0.5
0.01	0.1	0	0.1	0.02	0.498	1
0.01	0.1	0	0.1	0.02	0.498	1
0.01	0.1	0	0.1	0.02	0.498	1
0.01	0.1	0	0.1	0.02	0.498	1
0.01	0.1	0	0.1	0.02	0.498	1
0.01	0.1	0	0.1	0.02	0.498	1

Scope Lie #2 Your digital scope's noise specification

Today's digital scopes only provide a 5 or 10mV/division setting and use a digital zoom to "get down to" a 1mV/division setting. This tactic significantly increases noise while lowering the accuracy. As a way to reduce the noise, some oscilloscopes limit bandwidth on low volts per division settings, while others do not offer the 1mV/division setting at all.



Try the scope that has a true, low noise performance and highly accurate 1mV/division setting.

Discover how your digital scope may be misrepresenting results at

www.rohde-schwarz-scopes.com

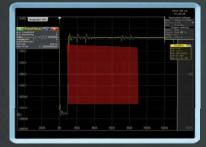
888-837-8772



Scope Lie #3

Your digital scope's update rate

Digital scope manufacturers boast update rates of 1+ million waveforms/sec, but this spec excludes measurements and mask testing. These demanding scope measurement tests slow down the update rate of most digital oscilloscopes. When conducting a mask test at lower update rates, finding an event that occurs once per second could take anywhere from minutes to hours.



Try the scope that maintains extremely high waveform update rates while performing a mask test, and locates the error in less than 30 seconds.

Discover how your digital scope may be misrepresenting results at

www.rohde-schwarz-scopes.com

888-837-8772





AC ERRORS ARE MORE SUBTLE, MORE DIFFICULT TO UNDERSTAND, AND MORE SERIOUS, ESPECIALLY FOR SIGNAL CHAINS IN 'SCOPES.

rail. For the parts that operate over the rails, such as the LT1638 op amp, the company guarantees the common-mode voltage even above the positive supply. For purpose-built, high-side-current-sense amplifiers, such as the LTC6101, Linear doesn't even spec CMRR, says Regan. Instead, the company provides a PSRR (power-supply-rejection-ratio) spec—the amount of change in the power-supply voltage—because the inputs connect to the positive supply, and they all move together.

Input offsets, bias currents, gain errors, PSRR, and common-mode errors are just a few of the specs that create dc error in your system. The antialiasing filter may cause similar errors if it uses op amps in active configurations. The level-shifting amplifier, which also serves as a buffer for the ADC, also has most of these error terms. Because the first amplifier in the signal chain amplifies the signal, the errors of the filter and the level-shifting amplifier tend to contribute less to total system error, but you still must account for them in your error budget.

When you finally get to the ADC,

you can look at the dc specs, such as integral linearity and monotonicity. The ADC's internal or external reference also has dc errors that must be included in your budget. It's usually a good idea and worth the expense to use a high-quality reference because doing so eliminates the need for factory calibrations or any subsequent field adjustments. Potentiometers and trimmers have low reliability, so you may want to incorporate digital potentiometers or DACs to perform the trimming instead of using a mechanical part.

AC ERRORS COME NEXT

Understanding and tabulating all of the dc errors in the analog-signal path are complex tasks, but ac errors are even more subtle, more difficult to understand, and more serious, especially for signal chains such as those in oscilloscopes. Errors on the ac component of a signal occur at all points in the analog-signal chain. Your circuitry also has ac-error sources in the clock circuit that operates the ADC. Just as daunting, errors in the signal can result from the presence of ac

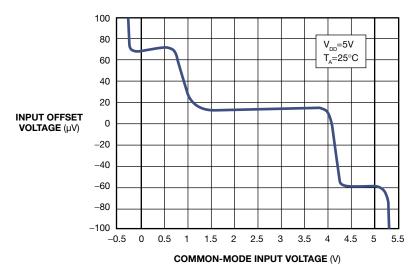


Figure 4 Like most other rail-to-rail-input parts, the TLV2450 amplifier has a dual differential-pair front end, causing the offset voltage and the offset current to change with common-mode input voltage (courtesy Texas Instruments).

noise on the power-supply circuits that feed analog chips.

It helps to look at the error sources from the outputs to the circuit's input. The last analog IC in the signal path is usually an ADC. Examine its ac specs to see whether it can meet your application's needs as it operates as an acsampling system on the ac signal.

One key spec is the ADC's ENOB (effective number of bits) at a given sampling frequency. For accurate 10-bit measurements, start with a converter that has an ENOB greater than 10.

Otherwise, the rest of the signal chain will further degrade the 10-bit accuracy. Ensure that the converter's bandwidth is as high as the highest frequencies you need to accurately measure. ENOB is a simple way for manufacturers to express the ADC's SNR (signal-to-noise ratio) during operation. You may want to look at pin-compatible converters that come in 12-, 14-, and 16-bit versions so that your board's layout remains the same even if you have to increase the number of bits in the converter.

A buffer and a level-shifting circuit

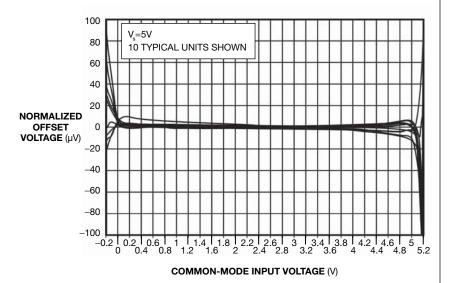


Figure 5 The OPA369 amplifier uses a charge-pump front end, reducing the offset-voltage change over the common-mode input voltage (courtesy Texas Instruments).

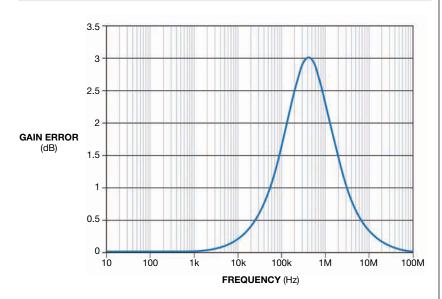
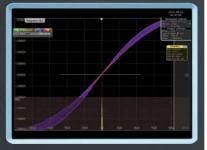


Figure 6 A significant gain error occurs over frequency because an amplifier's open-loop gain rolls off at higher frequencies (courtesy Texas Instruments).

Scope Lie #4 Your digital scope's analog trigger

Most analog and digital scopes utilize separate circuits for trigger and waveform acquisition. These circuits have different bandwidths, varying sensitivities and diverse characteristics which can cause trigger jitter.

The R&S®RTO digital oscilloscope does not split the captured signal into a trigger circuit and acquisition circuit, virtually eliminating trigger jitter and enabling you to trigger on any specified trigger point.



Try the scope with the digital trigger, that triggers on the same waveform you see on the screen.

Discover how your digital scope may be misrepresenting results at

www.rohde-schwarz-scopes.com

888-837-8772



COMPONENT TOLERANCES

Resistor tolerances in input attenuators create dc errors, and capacitors in the attenuators create a significant amount of ac errors (Figure A). For this reason, you must use discrete capacitors in the input attenuator to swamp out all the stray capacitance in the PCB (printed-circuit board) and in the multiplexer's input pins. Placing three capacitors in parallel with the resistors makes an ac-voltage divider alongside the dc-voltage divider that the resistors create. The capacitor ladder lowers the input impedance at higher frequencies. You must evaluate whether that lower impedance will cause a problem in your measurement system. If so, you must design a different input-attenuator structure. No matter what input structure you use, you must calibrate out the stray-capacitance-induced ac errors. For this reason, it is difficult to achieve both high-impedance inputs and high ac accuracy.

A Monte Carlo Spice simulation of the input attenuator shows serious ac errors in the attenuator at low frequencies (Figure B). You might think that picofarads of capacitance would not make much difference, but they make a big difference at megahertz frequencies. This high-impedance input structure has nominal 1-M Ω input impedance. It takes little capacitor tolerance to create significant errors, and those errors double the nominal dc-error terms at frequencies as low as 2 kHz (Figure C).

Other results of using an input attenuator are less intuitive. You don't necessarily need to use 0.1%-tolerant resistors to achieve a 0.1%-accurate output. A large difference in resistor values means that the tolerance of the larger-value resistor will dominate the output accuracy. Think of a voltage divider with a 100,000-to-1 difference. You could fashion

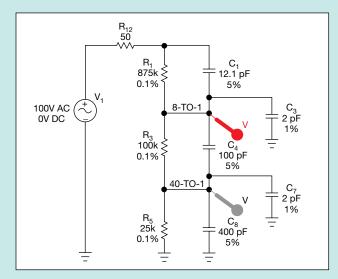


Figure A You can model your input attenuator network in Cadence's Orcad Capture for a Spice simulation. R_{12} is the source resistance of your signal. Discrete capacitors C_1 , C_4 , and C_8 comprise an ac divider. C_3 and C_7 represent the PCB's and ICs' stray capacitance.

this voltage ladder with a 10 Ω resistor and a 999,990 Ω resistor. You could use a 0.1%-tolerant resistor for the 999,990 Ω resistor and a 1%-accurate resistor for the 10 Ω resistor. Nevertheless, the output accuracy remains so close to 0.1% that you can round it to 0.1%. A 50%-accurate voltage ladder with equal-value resistors does require 0.1%-tolerant resistors to ensure a 0.1%-tolerant output voltage.

Vendors make resistors with laser trimming for tight tolerances; 1%-tolerant resistors are commonplace, and 0.1%-tolerant resistors are available. To get tighter tolerances, you can use custom resistors on ceramic substrates, such as those from Vishay and BI Technologies. This approach allows you to put multiple thin-film resistors on one substrate; the resistors then track each other over temperature. You can specify thin-film resistors on a single ceramic substrate that track each other to within 0.02%. The absolute-value tolerance of the resistors is 0.05%. This tolerance figure should not pose a problem because you should design your measurement channel so that the ratio of resistors determines a measurement attenuation or gain.

Thin-film ceramic resistors can achieve tighter ratiometric tolerances, such as 0.01%, but cost becomes a factor. Instead, you might investigate using an IC that has built-in resistors, such as those from Linear Technology, Maxim, and Analog Devices. Bear in mind, however, that you cannot just blindly accept the tolerance ranges on the data sheet. You must solder a statistically significant batch of parts onto your PCB and determine whether your soldering process degrades resistor tolerance. If assembling the PCB into an enclosure causes stress or warping, these problems also affect the tolerances of all of the resistors on your PCB, even those inside an IC.

An error-budget spreadsheet is just a nominal starting point to add up all the inaccuracy in your signal path. If the worst-case resistor tolerance goes from 0.2 to 0.3% after soldering, then you must use the 0.3% value in your spreadsheet.

Manufacturers can trim carbon and metal-film resistors but not carbon-composition or wire-wound devices-during manufacturing. They can measure carbon and wire-wound types only after manufacturing; they then separate the resistors into tolerance bins (Reference A), creating an unusual situation (Figure D). With 10 or 20 carbon-composition resistors in a signal chain, you might think that the entire signal path will have a gaussian distribution of accuracy. Unless you use the most accurate grade a manufacturer offers, however, this scenario is unrealistic because the vendor makes all the resistors in a batch, measures them, puts all of the 1%-tolerant resistors into a bin, and sells them for a higher price. As a result, you cannot count on any resistors in the 5%- or 10%-tolerant line to be the exact value that vou want. The vendor removes all of the close-tolerance resistors to sell as 1%-tolerant parts.

48 EDN | OCTOBER 20, 2011 [www.edn.com]

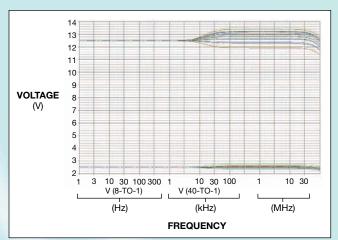


Figure B The PSpice Monte Carlo simulation of the input attenuator shows significant ac errors as low as 10 kHz.

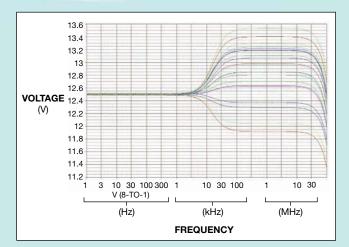


Figure C This expanded view of the simulation demonstrates the difficulty of high-impedance measurement inputs. Even the capacitors' small tolerance changes greatly affect the accuracy at frequencies as low as 3 kHz. Attenuator capacitances react with the source impedance to corrupt measurements at frequencies higher than 30 MHz.

Hence, the distribution of resistor values in the 10% line is not gaussian; it is more like a bathtub distribution with parts that are greater than 5% at a high level and those lower than 5% at a low level. All of the parts are within 10%, but this skewed distribution means that the measurement chain almost never averages out to a tolerance nearing 0%.

If you only rarely use carbon-composition or wire-wound resistors, this problem may seem unimportant, but it occurs in almost all factory-binned parts. Manufacturers select the close-tolerance parts and sell them for higher prices. This scenario can apply to op amps and other active parts.

Capacitor vendors specify looser tolerances on their parts than those of resistors because the vendors cannot automatically trim capacitors during production. They make film

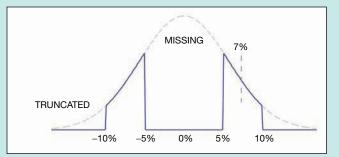


Figure D Manufacturers bin components and ICs in tolerance levels, removing the low-tolerance parts and selling them at higher grades (courtesy Howard Johnson, PhD).

capacitors by winding a roll of film into a cylindrical shape. They can precisely control the area of the film, but the thickness of the film varies slightly due to the exigencies and vicissitudes of manufacturing. Film-capacitor vendors just roll up the capacitors and measure them so that they can place them into 10%-, 5%-, and 1%-tolerant bins. Manufacturers of carbon-composition and wire-wound resistors face a similar problem.

Ceramic capacitors have similar manufacturing variability. Ceramic-capacitor vendors can control the area and layers of the parts but not the distance between the plates of the capacitor after sintering in a high-temperature oven.

Semiconductor junctions form capacitors in a signal chain and behave as varactors. Their capacitance changes depending on the amplitude of the applied voltage, much like a tuning capacitor in a radio. The varying capacitance changes the ac error in your system depending on the signal that is passing through. It can be difficult to minimize these errors and may require you to add compensation components or remove the errors in software.

Inductors are as problematic as capacitors. You must manually select any magnetic inductor to get 1% tolerance. If you are designing high-frequency circuits with air-core inductors, you might be able to ensure that the inductors you buy have tight tolerance, but these parts also cost more than 5%- or 10%-accurate parts.

The fact that precision resistors are much less expensive than precision capacitors and inductors will affect your design choices. Use tighter-value resistors if it allows you to loosen the spec on your capacitors and inductors. Accurate resistors often cost 10 times less than accurate inductors and capacitors. Avoid using mechanical potentiometers or trimming capacitors. After electrolytic and tantalum capacitors, these parts are the least reliable in electronic systems. AVX and Johanson Technology make capacitors you can laser-trim during manufacturing. Their reliability is similar to that of a conventional ceramic capacitor.

REFERENCE

Johnson, Howard, "7% solution," *EDN*, June 10, 2010, pg 22, http://bit.ly/p14yVv.

[www.edn.com] OCTOBER 20, 2011 | EDN 49



The secret of business is knowing something nobody else knows. 55

- Aristotle Onassis

Know more. Business moves on information. Having the inside track on a technology trend, a merger, or that next start-up can make all the difference to your business. Our award-winning editorial team provides timely global coverage of the companies, events and people that will drive the electronics industry, and delivers it directly to you.

EE Times Confidential is the unique source of vital business intelligence that will keep you a step ahead.

Every issue of EE Times Confidential includes:



The Big Idea: Business models, ecosystems and technology trends



Lay of the Land: News on emerging market segments



IP Landscape: IP trends and litigation news



EET on the QT: The inside scoop on deals, partnerships and who's who



VC Watch: Track investments in new companies



Market Data: Pricing, inventory and more

subscribe today

and receive 10% OFF your annual subscription.





SI

Details on annual subscription rates, two-year subscriptions and corporate subscriptions at www.eetimesconfidential.com or call (516) 562-5843.





sit just in front of the ADC. The nonideal op amp in this functional block creates ac errors. The dc-gain-error analysis shows that the ratio between open- and closed-loop gain creates substantial gain errors. These errors become worse at higher frequencies because of single-pole gain roll-off, in which the

age references that they use in their highaccuracy voltmeters. They solder their reference ICs onto carrier boards or into settled to a final value. Determining an adequate time for this initial drift to run

Tektronix all perform this task with voltthe main PCBs. They then apply power to the chip until the part's initial drift has



EVERY PIECE OF TEST EQUIPMENT IN YOUR LAB HAS A CALIBRATION SCHEDULE. YOU SHOULD ALSO PROVIDE YOUR OWN CALIBRATION.

open-loop gain falls to one at the unity-gain-bandwidth point. So the faster you operate any operational amplifier, the less gain ratio there is between the open-loop and the closed-loop gain. You must factor this frequency-dependent error term into your error budget.

Several published sources exist for ac analysis (references 6 and 7). If your application requires an accurate signal path, you must use op amps with significantly more bandwidth than your signals. Some designers dispense with amplifiers and instead couple and levelshift with a balun (balanced-unbalanced) transformer. Amplifiers exhibit significant amounts of closed-loop gain error when you feed them signals with frequency components near the unitygain point (Figure 6).

THE JOYS OF CALIBRATION

All of the dc and ac error sources combine with spec drift over time to reduce the accuracy of your measurements. For that reason, every piece of test equipment in your lab has a calibration schedule from the manufacturer. You should also provide your own calibration for your designs. "Calibration absolves a lot of sins," says Texas Instruments' Grohe.

The first calibration takes place in the factory during manufacture. This calibration may involve hand-selecting components to meet tighter accuracy specs than the vendor guarantees in the data sheet. Another facet of ensuring accuracy in manufacturing is burning in key components for hundreds or even thousands of hours so that any initial drift occurs before you install the part in your system. Fluke, Agilent Technologies, and

its course is a science unto itself. Testequipment manufacturers keep longterm records of various reference ICs they sample from production. IC manufacturers cannot perform a die reduction or a process change without notifying the test-equipment manufacturer. Test companies also buy references from vendors they are not using in production to see whether their data sheets' drift claims are realistic.

Providing an accurate signal chain is difficult, especially in high-impedance systems. One way to handle the problem is to use an analog front end to interface with the sensors in your design. Texas Instruments' LMP91000 analog front end, for example, handles high-impedance inputs and performs signal conditioning and calibration. The company's LMP90xxx and Maxim's MAX1457 family handle resistivebridge sensors and perform excitation and measurement. ZMDI's ZSI21013 analog front end, like Maxim's parts, performs linearization using an integrated EEPROM. For inductive sensors, you might consider Microchip's MCP2036. Maxim, Analog Devices, and Intersil offer analog front ends for image sensing, and Irvine Sensors' MS3110 capacitance-sensor IC can resolve to capacitances as low as attofarads and has an on-chip EEPROM to store trimming and program settings. The e2v CPIC2.0 for MEMS (microelectromechanicalsystem) transducers has 30-aF resolution, and austriamicrosystems' AS1716 capacitive-sensor front end senses



[www.edn.com] OCTOBER 20, 2011 | EDN 51

CONNECT at the West Coast's Electronics Manufacturing Resource

Electronics

February 14-16, 2012

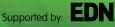
Anaheim Convention Center Anaheim, CA



Your face-to-face meeting place for electronics manufacturing solutions, including:

- Board Assembly Inspection
- Components
- Contract Services
- Production Machinery
- Software
- Subassemblies
- Test & Inspection Products
- ... and much more







Register online today at

FOR MORE INFORMATION

Agilent

www.agilent.com

Analog Devices www.analog.com

austriamicrosystems www.austriamicro systems.com

AVX

www.avx.com

BI Technologies www.bitechnologies.com

Cadence Design Systems

www.cadence.com

e2v

www.e2v.com

Fluke

www.fluke.com

Intersil

www.intersil.com

Irvine Sensors www.irvine-sensors. com

Johanson Technology www.johanson technology.com

Linear Technology www.linear.com

Maxim

www.maxim-ic.com

www.microchip.com

Tektronix www.tek.com

Texas Instruments www.ti.com

Vishay

www.vishay.com

ZMDI

www.zmdi.com

automotive-engine knock. Dozens of capacitive-sensor front ends target touch-sensing applications.

If an analog-front-end IC does not meet your needs, your design should provide for self-calibration wherever possible. Place a ground or a system common in the multiplexer and in the reference voltage and send the reference voltage into one of the multiplexer's channels. You may also want to send one or two key analog powersupply voltages into the multiplexer so that your product's software can apply known voltages and the system can measure its own power supply to calibrate out any errors. With an accurate voltage reference and clock, you know voltage and time. With accurate components for these two characteristics, you can derive other quantities, such as current, resistance, and slew rate. By carefully selecting your components, and using factory and field calibrations, you can keep your signal chain honest and trustworthy.**EDN**

REFERENCES

- "Op Amp Total Output Offset Voltage Calculations," *MT-039 Tutorial*, Analog Devices, October 2008, http://bit.ly/p9KDkn.
- Rauck, Robert L, "Differential Amplifier DC Analysis," Creative Power Resources, http://bit.ly/r4Ur02.
- Mancini, Ron, "Voltage like water: Working with low-voltage op amps," *EE Times*, Sept 1, 2001, http://bit.ly/oEtKQq.

- 4 "Notes On Gain-Error In Op-Amp Amplifiers," Electronix Express, http://bit.ly/qHmAXn.
- "Op Amp Open Loop Gain and Open Loop Gain Nonlinearity" *MT-044 Tutorial*, Analog Devices, Revision 0, October 2008, http://bit.ly/p5082M.
- "AC Error Equations for Operational Amplifiers," *Application Report SLOA061*, March 2001, Texas Instruments, http://bit.ly/qkeZGQ.
- Oljaca, Miroslav, and Henry Surtiha-

di, "Operational amplifier gain stability, Part 3: AC gain-error analysis," Texas Instruments, 2010, http://bit.ly/rg1xp2.

You can reach
Technical Editor
Paul Rako at
1-408-745-1994
and paul.rako@
ubm.com.





Finding the right solution to your company's materials needs has never been easier because now the companies of Brush Engineered Materials have unified under one name, Materion. It allows us to give you greater access to all of the resources and solutions we offer. So why not find out what the new Materion can do for you? Chances are we can make a big difference to your technologies and your bottom line. Find out more at materion.com.



Use reinforced isolation for effective data couplers

UNDERSTAND THE REQUIREMENTS AND MANDATES FOR ELECTRIC-SHOCK SAFETY WITH RESPECT TO THIS COMMON COMPONENT.

he primary tenet of electric-shock safety is that the equivalent of two independent insulation systems must lie between dangerously energized circuits and any conductor that a user of an electrical device can access. One of these insulation systems could be a safety-grounded enclosure with a single layer of internal insulation. Another approach is to use two insulation systems to provide redundant protection.

Complex electrical systems using the double-insulation approach require galvanically isolated communications across two layers of insulation without losing signal integrity. This requirement creates the need for devices with the equivalent electrical strength and reliability of two redundant-insulation systems. The so-called reinforced-insulation device relies on

a combination of construction, type testing, and continuous monitoring in production to ensure safety equivalence to two independent systems. This article examines how to achieve reinforced insulation in optocouplers and digital isolators with respect to construction and the test requirements of the IEC's (International Electrotechnical Commission's) IEC60950 and the related IEC60747-5-5 and VDE (Verband der Elektrotechnik, Elektronik und Informationstechnik)-0884-10, as well as differences with other accepted IEC standards for both types of isolators.

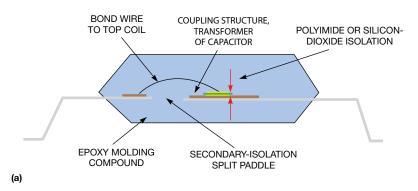
SAFETY ISOLATION

Modern systems require isolation to communicate with high-side components in battery-charging systems or motor drives, to break ground loops in communications systems, and to protect users from dangerous line or secondary voltages. The level of safety an application requires determines the level of isolation the application needs.

Functional isolation provides only the insulation necessary for the component to function properly but provides no protection to a user. Basic insulation provides a level of insulation from shock that is adequate for protecting an operator if the insulation is fully intact. However, to protect people from hazardous volt-

ages, regulations require double insulation: the stipulation that two independent insulation systems be present—basic insulation for shock protection and a supplemental layer so that, if a fault breaches one insulation system, a redundant system will still provide safety to the operator. When evaluating insulation systems, the primary requirement is safety, not electrical function, so the failure criterion during evaluation is whether the isolation barrier is intact after the qualification. It is an added bonus if the part still functions to the original specifications.

An example of a reinforced-insulation system is the feed-back-control loop in a power supply. Information about the output-voltage level must flow from the SELV (safety-extralow-voltage) side of the ac/dc converter to the line side of the power supply. Operators can be in contact with the SELV side



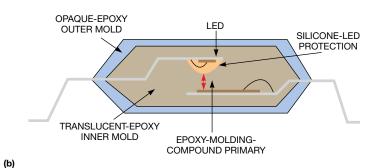


Figure 1 The component structure of both digital-isolator construction (a) and optoisolator construction (b) has reinforced insulation.

[www.edn.com] OCTOBER 20, 2011 | EDN 55

TABLE 1 CREEPAGE AND CLEARANCE REQUIREMENTS				
AC mains (V rms)	Mains category (V rms)	Class II transient voltage (V rms)	Basic creepage/ clearance (mm)	Reinforced creepage/ clearance (mm)
240	300	2500	2.5/2	5/4
400	600	4000	4/3.2	8/6.4

of the power supply, so two independent isolation systems or a reinforced-insulation system must be present in the datapaths to protect operators from shock.

Passive components, such as resistors or capacitors, can operate in series without significant functional degradation, but putting two data isolators into the path would be impractical for several reasons. First, analog data would lose fidelity, and digital data would have long propagation delays and added jitter. Second, this scenario would create the need for an intermediate power supply to run the coupler interfaces between the two layers of isolation. The impracticality of doubling up data-isolation devices creates the need for components that directly connect across a double-insulation boundary without sacrificing safety. The use of this type of component means that a system has reinforced insulation (Figure 1).

COMPONENT-LEVEL REQUIREMENTS

You can evaluate component-reinforced insulation either using the external dimensions of the component, such as creepage, clearance, and tracking index, or using internal electrical performance. Internal and external requirements are handled in very different ways. Creepage is the shortest distance along the surface of a component between electrically isolated conductive structures, such as component pins. Clearance is also the shortest distance between isolated conductive structures in a component, but it need not be on the surface, so the path can jump over grooves and be suspended over ridges.

In simple geometries, the creepage and clearance paths are often the same. Figure 1 shows the creepage path for a JEDEC Solid State Technology Association standard SOIC (small-outline integrated circuit) because many isolation devices use this style of package. The creepage and clearance for this package have the same path and length. Creepage is always greater than or equal to the clearance. An additional external property of components that is critical to insulation ratings is the CTI (comparative tracking index), a measure of how easily an insulating material will erode under electrical discharge. Higher tracking voltages will allow smaller creepage and still maintain safety.

External dimensions must be equivalent to the total distances that the basic and supplemental layers of a double-insulation system provide. In general, all creepage and clear-

Want to know what is important to your peers right now?

Have an opinion you want to get off your chest?

How about a pesky design question that another engineer may be able to answer?

Stay connected and informed with EDN on LinkedIn, Facebook, and Twitter.



EDN's Electronics Design Network group is the essential LinkedIn group for the full spectrum of information needed by design engineers, engineering managers, and upper management through each phase of the design cycle, from product-concept development to the manufacturing of electronics.

→ To join, log on to LinkedIn and type in "EDN's Electronics Design Network" under "Groups."



Become a fan of *EDN* on Facebook and join in discussions with your peers, keep track of industry events, and stay on top of news and trends.

To join, go to Facebook and type in "EDN: Voice of the Engineer."



Follow *EDN* on Twitter for real-time news updates, technical analysis, and quick tweets on our blogs, editors, and opportunities.

@EDNmagazine



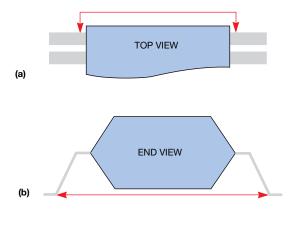


Figure 2 Two common operating conditions show the required package creepage (a) and clearance (b).

ance requirements are twice as large for reinforced components as for basic and supplemental components. Table 1 and Figure 2 show two common operating conditions and the required creepage and clearances. With this approach, the external environment and the surface properties determine the external spacing requirements, including the amount of expected contaminants, the air pressure, and tracking: the tendency of surface discharges to erode the outer surface of a component.

For internal properties of components, the quality of the insulation is more important than the quantity or the thickness of the insulation. The manufacturer can demonstrate that the part has the required electrical properties to withstand the voltage stresses in both the long term and the short term. The requirements of the IEC60950 standard are for office and telecom equipment and, to a large extent, for medical devices. You can readily verify the external dimensions and materials with a micrometer and some bulk material testing for a tracking index.

For internal requirements, you can use any of three approaches for qualifying the component. The simplest approach is to evaluate the component as if it contained only solid insulation. This approach requires that all of the internal distances through the insulation or along cemented joints are greater than 0.4 mm. No further type testing is required. However, it is difficult to make a high-performance data coupler that meets these requirements. It is widely believed that the 0.4-mm

minimum insulation thickness applies to all reinforced isolation devices, but it does not, and this misconception is a point of confusion for many engineers.

Another approach is to apply the rigorous IEC60747-55 standard, which qualifies optocouplers for reinforced insulation and has a battery of type tests and life tests with isolation-withstand verification tests after each one. This standard currently applies only to optocouplers, not other

newer digital isolators; however, VDE has created a draft standard, VDE0884-10, which applies the insulation tests of the IEC60747-5-5 standard to digital isolators.

Alternatively, you can treat the component as a semiconductor device. This category of devices has a set of type tests similar to the IEC60747-5-5 requirements. You use this approach with digital isolators because the testing requirements of the optocoupler standard target use in optocoupler structures.

Qualification to and maintenance of a reinforcement rating is accomplished in three phases. First, you evaluate materials and dimensions and conduct electrical type testing. Testing includes thermal cycling, limited life testing, and electrical overstress that would cause heating or catastrophic insulation failure. The integrity of the isolation is checked with a voltagewithstand test after each environment or test. IEC60747 type testing covers materials tests for CTI and flammability; electrical tests for withstand, partial discharge, insulation resistance, surge, and overload; and mechanical tests for thermal cycle, thermal shock, vibration, high-temperature storage, and creepage and clearance.

After the part receives approval based on its dimensions and type testing, a voltage-withstand test checks insulation integrity for each device during manufacture. IEC60747-5-5 and equivalent certifications perform a partial-discharge insulation-quality test on each device. The certifying body conducts periodic audits to verify that material sets and dimensions have not



changed and that calibrated equipment is properly conducting all assembly-line tests. The auditor may periodically repeat and review a sample of some of the tests.

TRENDS IN ISOLATION REQUIREMENTS

Different standards can have disparate requirements at the component level. One standard may even vary from edition to edition. This trend is becoming less problematic as IEC is moving toward a unified approach. This approach will likely take a significant amount of time to achieve because each standards committee has significant independence. A unifying trend in the application of system-level standards is the availability of component-level standards, such as IEC60747-5-5. If such a standard exists for a component, you can apply it instead of the requirements of a system-level standard.

The IEC and VDE standards set a high bar for reinforced insulation, including surge testing at levels of 10 kV or higher. Thin insulation layers cannot pass this test, which is the discriminating test for many optocouplers and digital isolators for qualification as reinforced insulation. Components that cannot meet the requirements usually fall back to the IEC60747-5-2 standard, which can be applied to basic insulation.

Yet another confusing point for designers of isolated systems is the assumption that an IEC60747-5 qualification automatically confers reinforced status. The IEC committees are currently working to revise the IEC60747-5-5 standard to include digital isolators. The next unified standard will be

applicable across all IEC system-level standards and should help to eliminate confusion in the future.

Manufacturers design and qualify reinforced insulation in data isolators to provide the protection of double-insulation systems and the data-transmission performance available with a single isolation barrier. Externally, the components have a creepage and clearance requirement that is twice the basic insulation requirement. Internally, insulation either meets the requirements of solid insulation, including through the insulation minimum distance, or it receives extensive type testing and assembly-line testing during production. The availability of a reinforced insulation rating that is verified by testing rather than detailed structural requirements allows innovation in insulation technology to be qualified without rewriting the standards for each new technology. EDN

ACKNOWLEDGMENT

This article originally appeared on EDN's sister site, Medical Designline, http://bit.ly/pmqj3s.

AUTHOR'S BIOGRAPHY



Mark Cantrell is an applications engineer for the digital-isolation group at Analog Devices Inc. His experience also includes six years at California Eastern Laboratories and 17 years at Lockheed Martin Missiles and Space. Cantrell received a master's degree in physics from Indiana University

(Bloomington, IN).

United States Postal Service

Statement of Ownership, Management, and Circulation (Requester Publications Only)

1. Publication Title: EDN 2. Publication Number: LISPS 74090 3. Filing Date: September 20, 2011 4. Issue Frequency: Semi-Monthly 5. No. of Issues Published Annually: 24 6. Annual Subscription Price: \$150 US, Canada, Mexico 7. Complete Mailing Address of Known Office of Publication: UBM LLC, 600 Community Drive, Manhasset, Nassau County, NY 11030-3875 8. Complete Mailing Address of House and Complete Mailing Address of Publisher: UBM LLC, 600 Community Drive, Manhasset, IN 11030-3875 9. Full Names and Complete Mailing Addresses of Publisher: Editor, and Managing Editor: Any Norcross, UBM LLC, 600 Community Drive, Manhasset, IN 11030-3875 9. Full Names and Complete Mailing Addresses of Publisher: Editor, and Managing Editor: Any Norcross, UBM LLC, 600 Community Drive, Manhasset, IN 11030-3875, UBM PLC, Ludgate House, 245 Blackfinas Road, London SE1 9UY, UK 11. Known Bondholders, Mortgaged and Other Security Holders Owing of Holding 1 Percent or More of Total Amount of Bonds, Mortgages, or Other Securities: None 12. The Purpose, Function, and Nonprofit Status of This Organization and the Exempt Status for Federal Income Tax Purposes: Has Not Changed During Preceding 12 Months 13. Publication Title: LED N14. Issue Date for Circulation Data: September 22, 2011

15. Extent and Nature of Circulation:	Average No. Copies Each Issue During Preceding 12 Months	No. Copies of Single Issue Published Nearest to Filing Date
a. Total Number of Copies (Net Press Run)	76,185	72,732
b. Legitimate Paid and/or Requested Distribution (by Mail and Outside the Mail)		
1. Outside County Paid/Requested Mail Subscriptions Stated on PS Form 3541	74,456	72,223
2. In-County Paid/Requested Mail Subscriptions Stated on PS Form 3541		
Sales Through Dealers and Carriers, Street Vendors, Counter Sales, and Other Paid or Requested Distribution Outside USPS	777	124
 Requested Copies Distributed by Other Mail Classes Through the USPS (e.g., First-Class Mail) 		
c. Total Paid and/or Requested Circulation (Sum of 15b (1), (2), (3), and (4))	75,233	72,347
d. Nonrequested Distribution (by Mail and Outside the Mail)		
1. Outside County Nonrequested Copies Stated on PS Form 3541	307	118
2. In-County Nonrequested Copies Stated on PS Form 3541		
 Nonrequested Copies Distributed Through the USPS by Other Classes of Mail (e.g., First-Class Mail, Nonrequestor Copies Mailed in Excess of 10% Limit Maile at Standard Mail or Package Service Rates) 	ed	
4. Nonrequested Copies Distributed Outside the Mail	59	0
e. Total Nonrequested Distribution (Sum of 15d (1), (2) and (3))	366	118
f. Total Distribution (Sum of 15c and e)	75599	72465
g. Copies Not Distributed	586	267
h. Total (Sum of 15f and g)	76185	72732
i. Percent Paid and/or Requested Circulation (15c divided by f times 100)	99.52	99.84
16. Publication of Statement of Ownership for a Requester Publication is required and	d will be printed in the O	ctober 20, 2011, issue of

this publication.

17. Signature and Title of Editor, Publisher, Business Manager, or Owner: Ken Bundy, Controller, September 20, 2011

I certify that all information furnished on this form is true and complete. I understand that anyone who furnishes false or misleading information on this form or who omits material or information requested on the form may be subject to criminal sanctions (including fines and imprisonment) and/or civil sanctions (including civil penalties).



58 **EDN** | OCTOBER 20, 2011 [www.edn.com]

RATED #1 Most Visited Website







Create a Brighter Future

Maxim's LED Drivers Enable Drop-In Replacements for Offline/MR16 Lamps



Maxim's solutions for dimmable offline (A, R, PAR, GU10, etc.) and MR16 LED retrofit lamps use a proprietary architecture to achieve flicker-free operation with dimmers and electronic transformers. This ensures compatibility with the existing electrical infrastructure, helping manufacturers overcome a critical obstacle to large-scale adoption.

Technology Benefits

- Smooth dimming with installed cut-angle dimmers from 0 to 100% brightness
- Flicker-free operation with most electronic transformers (MR16)
- Universal input (90VAC to 265VAC) allows a single lamp design to support worldwide infrastructure requirements (offline)
- Optional operation without electrolytic capacitors extends lamp lifetime

Find your LED driver solution at: www.maxim-ic.com/LED-info













Use a self-powered op amp to create a low-leakage rectifier

Martin Tomasz, Sageloop Designs, San Francisco, CA

You can combine a carefully chosen op amp, a low-threshold P-channel MOSFET, and two feedback resistors to make a rectifier circuit with less forward drop than a diode (Figure 1). The rectified output voltage powers the active circuitry, so no additional power supply is necessary. The circuit's quiescent current is lower than most Schottky diodes' reverse-leakage current. This circuit provides active rectification at voltage drops as low as 0.8V. At lower voltages, the MOSFET's body diode takes over as an ordinary diode.

The op-amp circuit turns on the MOSFET as a forward voltage develops between the input and the output voltages, according to the following equation:

$$V_{GATE} = V_{OUT} - (R_2/R_1)(V_{IN} - V_{OUT}),$$

where $V_{\rm GATE}$ is the MOSFET's gate drive, $V_{\rm IN}$ is the input voltage, and $V_{\rm OUT}$

is the output voltage. You can relate the input and the output voltages to the MOSFET's drain-to-source and gate-to-source voltages, according to the following equations:

$$V_{DS} = V_{IN} - V_{OUT}$$
 and $V_{GS} = V_{GATE} - V_{OUT}$,

where V_{DS} is the drain-to-source voltage and V_{GS} is the gate-to-source voltage. Combine these **equations** to relate the MOSFET's gate drive to a function of the drain-to-source voltage:

$$V_{GS} = -(R_2/R_1)V_{DS}$$

If you make R_2 12 times larger in value than R_1 , a 40-mV voltage drop across the MOSFET's drain-to-source voltage is sufficient to turn on the MOSFET at low drain currents (**Figure 2**). You could choose a higher ratio to further reduce the voltage drop within the limits of the op amp's worst-case

DIs Inside

- 62 Simple reverse-polarityprotection circuit has no voltage drop
- 64 Series-LC-tank VCO breaks tuning-range records
- ►To see all of *EDN*'s Design Ideas, visit www.edn.com/designideas.
- ► Have your own Design Idea to share? Find out how at http://bit.ly/ DesignIdeasGuide.

input-offset voltage of 6 mV. The op amp is powered from output-reservoir capacitor C_1 . The amplifier has rail-to-rail inputs and outputs and no phase inversion when operating near the rails. The amplifier operates at power-supply voltages as low as 0.8V. You directly connect the op amp's noninverting input to the $V_{\rm DD}$ rail and the amp's output to the gate of the MOSFET. The circuit consumes slightly more than 1 μA when actively rectifying a 100-Hz sine wave, less current leakage than that

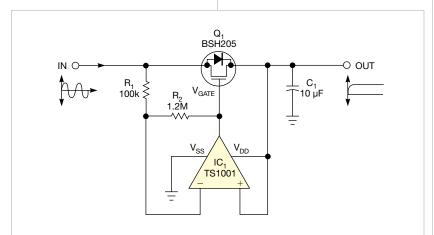


Figure 1 This circuit emulates a rectifier, but it has forward-voltage drop of 40 mV or less. The circuit has less reverse leakage than a Schottky diode.

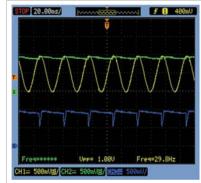


Figure 2 The output of the circuit (green) with a sine-wave input (yellow) shows that the FET's gate voltage (blue) drops out only when the input-to-output differential is less than 40 mV.

[www.edn.com] OCTOBER 20, 2011 | **EDN** 61

designideas

of most Schottky diodes. The BSH205 supports milliamp-level currents at a gate-to-source voltage of 0.8V.

The op amp's bandwidth limits the circuit to lower-frequency signals. At bandwidths higher than 500 Hz, the amplifier's gain begins to decline. As the signal frequency increases, the MOSFET remains off, and the body diode of the MOSFET takes over the rectification function. An input with a fast fall time could potentially drag the output with reverse current through the MOSFET. However, for small currents, the MOSFET operates in its subthreshold range. The amplifier quickly turns off due to the exponential relationship of the gate-to-source voltage to the drain-to-source current in the subthreshold range. The limiting factor is the amplifier's slew rate of 1.5V/msec. As long as you don't load the circuit so heavily that you drive the MOSFET into its linear range, reverse currents won't exceed forward currents.

You can use the circuit in a micropower solar-harvesting application (**Figure 3**). Depending on the light, the BPW34 cells generate 10 to 30 µA at 0.8

to 1.5V. The active-diode circuit rectifies the peak harvested voltage in conditions of rapidly changing light and minimizes reverse leakage to the cells. **EDN**

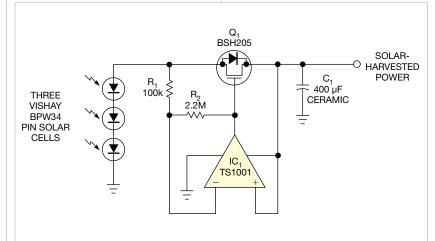


Figure 3 You can use the active-rectifier circuit to charge a capacitor from solar cells. The rectifier has low voltage drop and protects the cells from reverse current when there is no light.

Simple reverse-polarity-protection circuit has no voltage drop

Aruna Prabath Rubasinghe, University of Moratuwa, Moratuwa, Sri Lanka

Common methods of reverse-voltage protection employ diodes to prevent damage to a circuit. In one approach, a series diode allows current to flow only if the correct polarity is applied (Figure 1). You can also use a diode bridge to rectify the input so that your circuit always receives the correct polar-

ity (Figure 2). The drawback of these approaches is that they waste power in the voltage drop across the diodes. With an input current of 1A, the circuit in Figure 1 wastes 0.7W, and the circuit in Figure 2 wastes 1.4W. This Design Idea

suggests a simple method that has no

voltage drop or wasted power (Figure 3).

Select a relay to operate with the reverse-polarity voltage. For example, use a 12V relay for a 12V supply system. When you apply correct polarity to the circuit, D_1 becomes reverse-biased, and the S_1 relay remains off. Then connect the input- and output-power lines to the normally connected pins of the relay, so current flows to the end circuit. Diode D_1 blocks power to the relay, and the protection circuit dissipates no power.

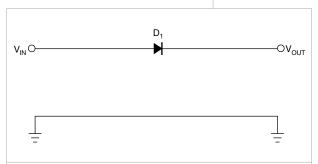


Figure 1 A series diode protects systems from reverse polarity but wastes power in diode losses.

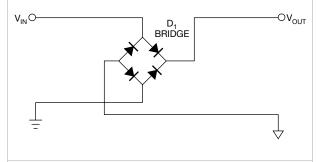


Figure 2 You can use a bridge rectifier so that your system works no matter what the input polarity is. This circuit wastes twice the power, in diode losses, of the circuit in Figure 1.

When you apply incorrect reversed polarity, diode D₁ becomes forward-biased, turning on the relay (**Figure 4**). Turning on the relay cuts the power supply to the end circuit, and red LED

D₃ turns on, indicating a reverse voltage. The circuit consumes power only if reverse polarity is applied. Unlike FETs or semiconductor switches, relay contact switches have low on-resistance,

meaning that they cause no voltage drop between the input supply and the circuit requiring protection. Thus, the design is suitable for systems with tight voltage margins. EDN

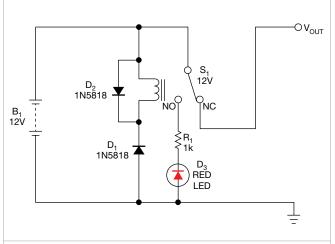


Figure 3 You can wire a relay switch to pass power to your system with no power loss. D₂ clamps inductive kicks from the relay coil.

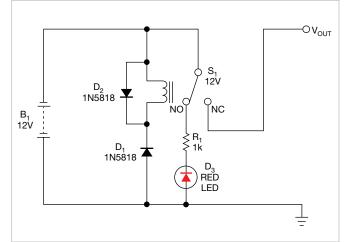


Figure 4 With reversed input voltage, the relay switch engages, interrupting power to the system, and the LED lights.



[www.edn.com] OCTOBER 20, 2011 | EDN 63



SURFACE MOUNT
(and thru-hole)
Transformers
& Inductors

Size <u>does</u> matter!



from lowprofile .19"ht.

- Audio Transformers
- Pulse Transformers
- DC-DC Converter
 Transformers
- MultiPlex Data Bus Transformers
- Power & EMI Inductors



or send direct for free PICO Catalog Call Toll Free 800 431-1064 Fax 914-738-8225

E Mail: info@picoelectronics.com

PICO Electronics, Inc.

143 Sparks Ave. Pelham, N.Y. 10803-1837







Delivery - Stock to one week

designideas

Series-LC-tank VCO breaks tuning-range records

Louis Vlemincq, Belgacom, Evere, Belgium

This Design Idea applies a novel topology to an oscillator. It uses a series-connected LC (inductivecapacitive) tank circuit to give the circuit a higher tuning range than circuits that use a parallel-LC connection. The architecture of the oscillator permits wide frequency swings, well beyond the capabilities of the best hyperabrupt varactor. Engineers deem a VCO (voltage-controlled oscillator) capable of covering one octave as state of the art. This topology allows a 4-to-1 ratio in output frequency. The LC tank alone sets this frequency so that the parasitic capacitances of other components do not limit the output frequency. Unlike standard oscillators, this circuit works well at its frequency extremes.

At first glance, the central structure of the oscillator resembles two transistors that form a latching SCR (siliconcontrolled-rectifier) structure (Figure 1). The structure is similar to that of a thyristor, but you add degeneration resistors that keep the circuit in a linear mode of operation. The resistors make the gain of this "SCR" smaller than one, and it is dc-stable. The series-tuned tank circuit increases the gain beyond one at the resonant frequency, causing the circuit to oscillate. No auxiliary

components are necessary for oscillation, and the node between the inductor and the capacitor is free of other connections, meaning that only the varactor you use as the capacitor determines the tuning range. The frequency varies as the square root of the tuning elements. To change the frequency by a factor of two, you need a fourfold variation of the tuning capacitance.

Unlike a parallel-LC tank, the resonant current passes through the active element and is, therefore, limited. This limit in turn means that the ac voltage appearing across the tuning components is small—typically, less than 100 mV. The small signal reduces the effects of circuit nonlinearity and the impact of the self-biasing effects of the signal on the varactor. You can use control voltages as small as 0.3V across the varactor. If you use a $1-\mu H$ inductor, the circuit still oscillates with capacitor values of $4.7~\mu F$ —a ratio of 106-to-1.

For the detailed design, move the LC tank to the emitter of PNP transistor Q_2 (**Figure 2**). The lower speed of the PNP creates greater phase difference and encourages oscillation. Connect L_2 and C_2 at a common power point on the power rail, emphasizing

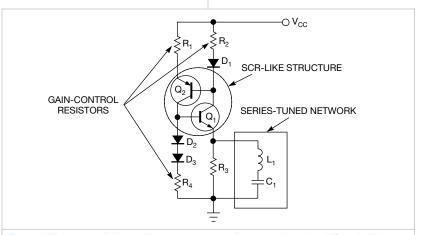


Figure 1 The heart of the oscillator are two transistors and a series-LC tank. The gain-control resistors add degeneration so that the transistors operate in their linear range instead of latching, as an SCR would.

DOW ECOLIBRIUM LETS THEM MAKE EXACTLY WHAT THEY'RE MAKING NOW. GREENER. The same home appliances, but with 40% fewer greenhouse gases. The same

electrical and electronic components, but with safer end-of-life disposal. The same automotive components, but with higher flame resistance. The same building materials, but with one more way to earn carbon credits and environmental certifications. ♦ DOW ECOLIBRIUM™ bio-based plasticizers are phthalate-free and RoHS compliant. They provide the same performance, feel and flexibility of the materials manufacturers are using now, while meeting strict regulatory requirements for flame resistance and safer end-of-life disposal. ♦ No matter what they make, they can make it greener with DOW ECOLIBRIUM.



designideas

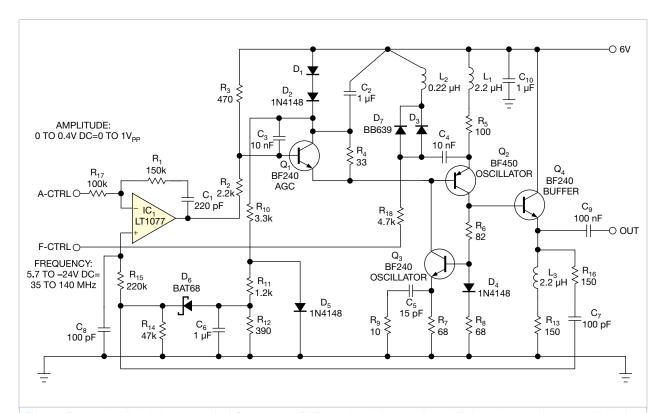


Figure 2 For the detailed design, move the LC tank to the PNP transistor. Varactors D_7 and D_3 form the capacitance, and L_2 is the inductance.

the criticality of the layout in this part of the circuit. The oscillator "senses" the tuned circuit through C_2 and C_4 , and anything inside that loop adds uncontrolled parasitics to L_2 . These parasitics would compromise the AGC (automatic-gain-control) action and degrade the performance and accuracy of the oscillator.

 $Q_{_{\rm I}}$ and associated components implement the AGC. A parallel-LC

oscillator tolerates clipping of the signal, but this series-LC circuit degenerates into a multivibrator if you allow the signal to grow so large that it clips. The AGC servo action has the added advantage of producing uniform output amplitude. Use D_5 to create a 0.6V dc bias. R_{11} and R_{12} form a voltage ladder that creates a dc-bias voltage close to the forward-voltage drop of Schottky diode D_6 . This bias allows D_6 to work

as a more perfect rectifier of the small output signal. C_8 integrates the rectified signal into a dc voltage proportional to the amplitude of the circuit's output. Apply this dc signal to IC_1 , the AGC amplifier, through a filter comprising R_{15} and C_8 . The op amp servo-controls the filtered dc signal against the A-CTRL input-amplitude signal you send to the circuit. This signal allows you to set output amplitude at 0 to 1V.

amplitude is 0.9V. The frequency range extends from 35 to 140 MHz, a 1-to-4 ratio—twice that of conventional high-performance VCOs—and requires a fourfold increase in the capacitance ratio. The overall capacitance ratio is 1-to-16, exactly that of the varactor itself. At the lowest (Figure 3) and highest (Figure 4) frequencies of the

output range, the quality of the

sine wave remains excellent,

thanks to AGC action. EDN

In this example, the output

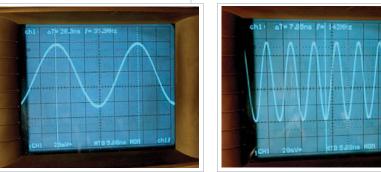


Figure 3 At 35 MHz and 0.9V output, the oscillator creates a high-quality sine wave.

Figure 4 At 142 MHz and 0.9V, the output is still pure and stable, thanks to the AGC circuit.

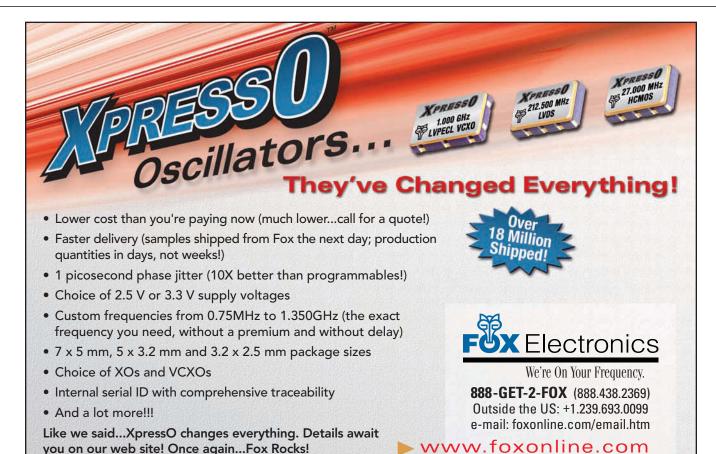
productroundup

AMPLIFIERS, OSCILLATORS, AND MIXERS



Microchip expands autozero-op-amp line with MCP6V2X family

The MCP6V2X family of op amps features a self-correcting autozero architecture, which enables high precision, including an input offset voltage of 2 μV and a gain-bandwidth product of 2 MHz. With noise of 50 nV/νHz, the MCP6V2X family has 2.3 to 5.5V operating voltages, and the devices' rail-to-rail I/O structure allows for full-range use, even in low-supply conditions. The devices are available in eight-pin MSOPs and suit use in consumer, industrial, and medical applications. The MCP6V26 and MCP6V28



productroundup

are available in eight-pin SOIC, MSOP, and 2×3-mm TDFN packages and sell for \$1.13 and \$1.18 (10,000), respectively. The MCP6V27 is available in eight-pin SOIC, MSOP, and 4×4-mm DFN packages for \$1.73 (10,000).

Microchip, www.microchip.com

ADI's ADA4096-2 op amp solves precision/ OVP trade-off problem

The ADA4096-2 dual op amp offers high precision along with ±30V of integrated input OVP (overvoltage protection). This level of internal OVP for inputs means that analog designers using the ADA4096-2 can eliminate or minimize the need for external OVP design and components. The op amp targets industrial sensors and other applications needing precision



signal handling, high accuracy, and ultralow power consumption. The ADA4096-2 draws 60 µA of power per

amplifier and features twice the bandwidth and half the voltage noise of its competitors, according to the vendor. The device sells for \$1.87 (1000).

Analog Devices, www.analog.com

TI's 36V OPA2188 op amp touts zero drift

The 36V OPA2188 op amp finds use in high- and low-voltagesupply applications requiring high precision, such as test-and-measurement equipment, electronic weigh scales, medical instrumentation, and flow meters. The device's zero-drift, 0.03μV/°C architecture reduces the need for future system calibration, and its initial offset voltage of 25 µV enables highresolution sensor measurements. The OPA2188 provides 2 MHz of bandwidth and consumes 475 µA of quiescent current, providing high accuracy. For high system precision, the device achieves low noise of 8.8 nV/√Hz. An input common-mode range extends from the negative rail to within 1.5V of the positive rail, eliminating the need for addi-



tional circuitry and enabling 5V, single-supply operation. The OPA 2188 is available in a 3×5-mm MSOP

or a 5×6-mm SOIC package for a suggested retail proce of \$1.40 (1000).

Texas Instruments, www.ti.com

Linear Tech's LTC6360 op amp drives SAR ADCs to 0V on 5V supply

The LTC6360 op amp drives 16and 18-bit SAR ADCs. It can drive to 0V and maintain high linearity on a 5V supply through its integrated ultra-low-noise charge pump. Maximum input offset voltage is less than 250 µV, and noise is $2.3 \text{ nV}/\sqrt{\text{Hz}}$. The device settles to 16 bits in 150 nsec and achieves a closed-loop -3-dB bandwidth of 250 MHz. Second- and third-harmonic-distortion figures are -103 and -109 dBc, respectively, at an input frequency of 40 kHz. The output drives a series- 10Ω resistor/330-pF-capacitor-filter network and can drive larger load capacitances. The LTC6360 is available in MSOP and 3×3-mm, eight-pin DFN packages and operates over the 0 to 70°C commercial, -40 to +85°C industrial, and -40 to +125°C extended temperature ranges. Prices start at \$2.19 (1000).

Linear Technology, www.linear.com

TI's LMH6522 amps target wideband-radio systems

TheLMH6522 quadandLMH6521 dual digital variable-gain amps suit use in multichannel wideband wireless systems. The amps feature output-third-order-intercept points of 49 and 48.5 dBm, respectively, at a 200-MHz input frequency. They offer 1- and 0.5-dB gain steps over 31- and 31.5-dB

ranges and noise figures of 8.5 and 7.3 dB, respectively, at maximum gain. The LMH6522 and LMH6521 come in 54-and 32-pin LLPs and sell for \$9.85 and \$6.15 (1000), respectively.

Texas Instruments, www.ti.com

EDN ADVERTISER INDEX

Company	Page			
Agilent Technologies	C-3			
Analog Devices	19,41			
austriamicrosystems AG	63			
Avnet	29			
Avtech Electrosystems Ltd	69			
Centellax	3			
Coilcraft	4			
Credit Management Assoc	69			
CUI Inc	42			
Digi-Key Corp	C-1, C-2, 59			
Dow Electrical & Telecommunications	65			
Everlight Electronics Co Ltd	11			
Fox Electronics	67			
Hapro Inc	69			
Integrated Device Technology	13			
International Rectifier	7			
Keystone Electronics	53			
Lattice Semiconductor	17			
Linear Technology	C-4			
Materion Corp	54			
MathWorks	27			
Maxim Integrated Products	60			
Memory Protection Devices	58			
Micro Crystal AG	40			
Mornsun Guangzhou Science & Technology Co Ltd	51			
Mouser Electronics	6			
National Instruments	14			
Panasonic Industrial	69			
Pickering Electronics Ltd	37			
Pico Electronics Inc	10, 57, 64			
Rohde & Schwarz	43, 44, 45, 46, 47			
Rohde & Schwarz Gmbh & Co KG	21, 23, 25			
Tektronix	31, 33, 35			
Trilogy Design	69			
UBM <i>EDN</i>	50, 52, 56			
Vicor Corp	8			
EDN provides this index as an additional service. The publisher assumes no liability for errors or omissions.				

publisher assumes no liability for errors or omissions.

68 **EDN** | OCTOBER 20, 2011 [www.edn.com]

EDN

productmart

This advertising is for new and current products.









DESIGNER OF PERSONAL ORGANIZATIONAL PRODUCTS



CMA is soliciting offers for bulk purchase of assets remaining from operations of a designer/distributor of personal organizational accessories, power supply connectors for handheld digital electronic equipment and accessory stands. Assets include domestic and international inventories and receivables, intellectual property, customer lists, office furniture.

CMA has already received a written offer from a prospective purchaser for \$450,000.00. All overbids must be accompa-nied by a good-faith deposit of no less than \$30,000.00, which is subject to forfeiture if bidder fails to close within seven (7) days of confirmation as the successful bidder. Minimum overbid is \$480,000.00.

BID DEADLINE: October 28, 2011 at 11:00am (PDT)

For More Information Contact, Charles Klaus, 714-920-7848 CREDIT MANAGEMENT ASSOCIATION 40 E. Verdugo Ave., Burbank, CA 91502

Fast Pulse Test Solutions from AVTECH

Avtech offers over 500 standard models of high-speed pulse generators, function generators, and amplifiers ideal for both R&D and automated factory-floor testing.

AVR-CD1-B Reverse Recovery Test System



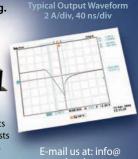
Some of our standard models:

AVR-EB4-B: +2A / -4A pulser for diode reverse-recovery time tests AV-156F-B: +10 Amp constant current pulser for airbag initiator tests **AVO-9A-B:** 200 mA, 200 ps rise time driver for pulsed laser diode tests AV-151J-B: ±400 V, 50 kHz function generator for piezoelectric tests **AVOZ-D2-B:** 700 V, 70 A pulser for production testing of attenuators

AVR-DV1-B: 1000 V, variable rise-time pulser for phototriac dV/dt tests

Pricing, manuals, datasheets: www.avtechpulse.com

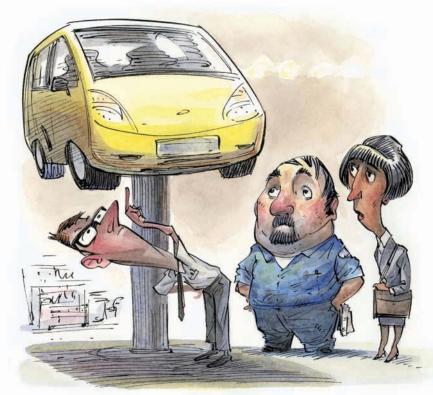
VTECH ELECTROSYSTEMS LTD. | Tel: 888-670-8729 PO Box 265 Ogdensburg, NY 13669 | Fax: 800-561-1970



E-mail us at: info@ avtechpulse.com

AVTECH

OCTOBER 20, 2011 | EDN 69 [www.edn.com]



MI/EMC (electromagnetic-interference/electromagnetic-compatibility) certification is among the toughest design milestones for embedded automotive controllers. My company once developed an 8-bit controller for air-path control of a direct-injection diesel engine. Engine-performance results were encouraging, so the next step was to approach the local certification agency for EMI/EMC-compliance testing. The EMI test was a piece of cake: An onboard 4-MHz crystal generated almost no RF interference.

As the engineer switched on the EMC chamber, we were almost certain that the unit would valiantly withstand the onslaught of strong RF radiation. When the controller reached 50 MHz, however, all of the outputs then turned

Suspecting a software error due to intense radiation, I checked the microcontroller's output pins. They were showing dead-on accurate logic levels. This finding pointed the needle of suspicion toward the Infineon TLE 6216 output chip. I couldn't believe that the chip would fail under EMC testing. When we withdrew the EMC-test radiations, the

outputs remained off. Apparently, they tripped due to an internal short circuit. As we power-cycled the controller, the outputs regained their correct logic levels. However, when EMC radiation was restored, the outputs immediately tripped again.

Postponing the EMC test until the next day, we took the unit to our laboratory for analysis. The chip outputs included RF-filter capacitors near the field connector.

I understand the purpose of RF input capacitors, but I have never believed that they should be near the poweroutput pins. I found it hard to believe that EMC radiation would corrupt low-impedance, high-power outputs. Nevertheless, we were religiously placing those capacitors, according to standard automotive-design tenets, at all field connections.

In view of our earlier problems, I checked the ground tracks of the capacitors. They terminated on a separate RF ground. However, RF ground and signal ground were supposed to connect through a small jumper near the power connector, but this prototype unit had a dry-soldered power connector. This finding answered my question regarding the role of the output capacitors: These output pins also included input circuits to sense overcurrents and short circuits to activate internal trip circuits for protection. EMC radiation can corrupt these input circuits, thus tripping the protection circuits.

We rectified the dry-solder problem and continued the test on the next day. This time, the output chip did not trip at all and obediently followed CPU commands for most of the frequencies from 1 to 400 MHz. However, the outputs were erratically tripping at frequencies higher than 400 MHz. Apparently, the low-cost filter capacitors that automotive applications typically use were not up to the task at those frequencies.

I also reviewed designs of other units we had developed that had passed this test. Most of them used output chips with short-circuit limits, which we could program through an SPI (serial-peripheral interface), such as an STMicroelectronics L9823 octal low-side driver. This driver would never cause an IC to trip its outputs during EMI and EMC testing. Using such a chip would have meant lengthy software and hardware modifications. Instead, we inserted inductive-bead filters in the output lines to suppress the high frequencies that were troubling us during the test. This measure was successfully able to guard all of our outputs from spurious tripping during the next EMC tests a few months later. EDN

Vishwas Vaidya heads an embeddeddesign team at Tata Motors (Pune, India).

"I need a function generator that generates confidence, too."





Scan the QR code or visit goo.gl/lgtJk to see a 33500 Series product tour

© 2011 Agilent Technologies, Inc.

Point-by-point technology = more confidence.

You're developing new technologies every day that are faster, more efficient and imaginative. Agilent 33520 Series function/arbitrary waveform generators provide your waveforms with the highest signal fidelity.

33521A and 33522A

30 MHz sine, square, pulse bandwidth

250 MSa/s, 16-bit sampling

Point-by-point arbitrary waveforms

Dual-channel coupling and tracking

With 10x better jitter than anything in its class you have unparalleled control of signal frequency. And point-by-point technology provides an unprecedented ability to generate arbitrary waveforms. That's confidence. That's Agilent.

Agilent and our
Distributor Network
Right Instrument.
Right Expertise.
Delivered Right Now.

TESTEQUITY

800-732-3457 www.testequity.com/agilent Get NEW App Note: Compare Direct Digital Synthesis vs. Point-by-Point Function Generator Performance www.testequity.com/Agilent Function



THE FUTURE IS



001010010111, .0010011001001 /1000111 0011100 /001110 1100100, /001000 0011100 /0100010 0100100, /0100010 11001100, /0100010 11001100, /0100010 0100101111100

\$54 BILLION*

For Three Decades We've Looked to the Future

Thirty years ago, at the dawn of the digital revolution, some questioned the wisdom of founding a company dedicated to delivering purely analog products. Since then, the worldwide analog market has grown twenty-fold. With this tailwind, Linear's growth as an industry leader is no mystery.

Innovation. Linear Technology wrote the book on analog innovation. From our power and Hot Swap^M devices to μ Module^M and energy harvesting products, we've provided our customers with enabling technology.

Focus. Our laser beam focus on designing the hard stuff for automotive, industrial and communications markets resulted in new products for the most demanding applications.

Technical Prowess. Early on, we recognized the importance of building a solid technical team. Our designers and applications engineers are second to none.

Support. Many say it; we deliver – on time, with the industry's shortest lead times.

Quality. Our products meet the data sheet specs – every time – with the industry's highest quality.

We're there for you, with the industry's highest performance analog products and the support you demand. Count on it.

\$2 BILLION

1981 ANALOG MARKET GROWTH

Source: World Semiconductor Trade Statistics *WSTS Analog Market Forecast, 2014





View a video with CEO Lothar Maier and Co-founders Bob Swanson and Bob Dobkin at www.linear.com/30vearinterview



\$44 BILLION

2011

LT, LT, LTC, LTM, Linear Technology, the Linear logo and µModule are registered trademarks and Hot Swap is a trademark of Linear Technology Corporation. All other trademarks are the property of their respective owner